

EV12DS130AZP EV12DS130BZP Low Power 12-bit 3 Gsps Digital to Analog Converter with 4/2:1 Multiplexer

Datasheet DS 60S 223692(K)



Main Features

- 12-bit Resolution
- 3 Gsps Guaranteed Conversion Rate
- 7 GHz Analog Output Bandwidth
- 4:1 or 2:1 integrated Parallel MUX (Selectable)
- Selectable Output Modes for performance optimization: Return to Zero, Non Return to Zero, Narrow Return to Zero, RF
- Low Latency Time: 3.5 Clock Cycles
- 1.4 Watt Power Dissipation in MUX 4:1 Mode
- Functions
 - Selectable MUX Ratio 4:1 (Full Speed), 2:1 (Half Speed)
 - Triple Majority Voting
 - User-friendly Functions:
 - Gain Adjustment
 - Input Data Check Bit (FPGA Timing Check)
 - Setup Time and Hold Time Violation Flags (STVF, HTVF)
 - Clock Phase Shift Select for Synchronization with DSP (PSS[2:0])

- Output Clock Division Selection (Possibility to Change the Division Ratio of the DSP Clock)

- Input Under Clocking Mode
- Diode for Die junction Temperature Monitoring
- LVDS Differential Data input and DSP Clock Output
- Analog Output Swing: $1V_{pp}$ Differential (100 Ω Differential Impedance)
- External Reset for Synchronization of Multiple MuxDACs
- Power Supplies: 3.3 V (Digital), 3.3V & 5.0V (Analog)
- FpBGA Package (15 × 15 mm Body Size, 1 mm Pitch)
- MSL 3 (Moisture Sensitivity Level)

Performances

Broadband: NPR at –14 dB Loading Factor, (See Section 7.2.7 "NPR Performance" on page 58)

- 1st Nyquist (NRTZ): NPR = 51.3 dB 10.0 Bit Equivalent at Fs = 3 Gsps
- 1st Nyquist (NRTZ): NPR = 55.7 dB 10.8 Bit Equivalent at Fs = 1.5 Gsps
- 2nd Nyquist (NRTZ or RTZ): NPR = 44.6 dB 8.9 Bit Equivalent at Fs = 3 Gsps
- 3rd Nyquist (RF): NPR = 42.5 dB 8.6 Bit Equivalent at Fs = 3 Gsps

Single Tone: (see Section 5. "Functional Description" on page 15)

- Performances Characterized for Fout from 100 MHz to 4500 MHz and from 2 Gsps to 3.2 Gsps
- Performance Industrially Screened Over 3 Nyquist Zones at 3 Gsps for Selected Fout.

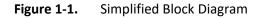
Step Response

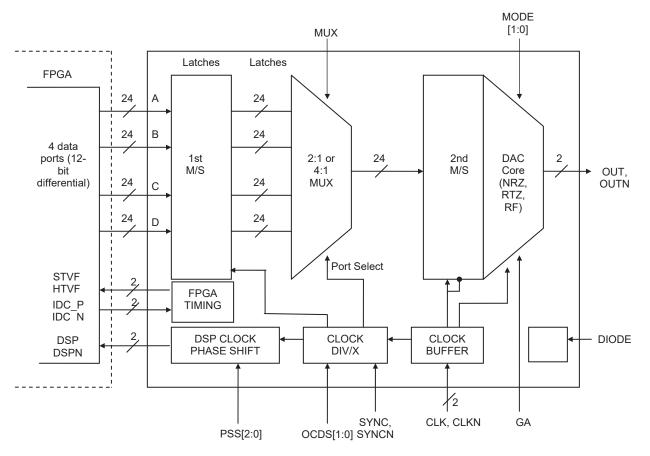
• Full Scale Rise /Fall Time 50 ps

Applications

- Direct Digital Synthesis for Broadband Applications (L-S and Lower C Band)
- Automatic Test Equipment (ATE)
- Arbitrary Waveform Generators
- Radar Waveform Signal Synthesis
- DOCSIS V3.0 Systems

1. BLOCK DIAGRAM





2. DESCRIPTION

The EV12DS130A/B is a 12-bit 3 Gsps DAC with an integrated 4:1 or 2:1 multiplexer, allowing easy interface with standard LVDS FPGAs thanks to user friendly features as OCDS, PSS.

It embeds different output modes (RTZ, NRZ, narrow RTZ, RF) that allow performance optimizations depending on the working Nyquist zone.

The Noise Power Ratio (NPR) performance, over more than 900 MHz instantaneous bandwidth, and the high linearity (SFDR, IMD) over full 1st Nyquist zone at 3 Gsps (NRZ feature), make this product well suited for high-end applications such as arbitrary waveform generators and broadband DDS systems.

3. ELECTRICAL CHARACTERISTICS

3.1 Absolute Maximum Ratings

Table 3-1.Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Positive Analog supply voltage	V _{CCA5}	6.0	V
Positive Analog supply voltage	V _{CCA3}	4.0	V
Positive Digital supply voltage	V _{CCD}	4.0	V
Digital inputs (on each single-ended input) and IDC, SYNC, signal Port P = A, B, C, D $V_{\rm IL}$ $V_{\rm IH}$ Digital Input maximum Differential mode swing	[P0P11], [PON P11N] IDC_P, IDC_N SYNC, SYNCN	GND–0.3 V _{CCA3} 2.0	V V V _{pp}
Master clock input (on each single-ended input) V _{IL} V _{IH} Master Clock Maximum Differential mode swing	CLK, CLKN	1.5 3.5 2.5	V V V _{pp}
Control functions inputs $V_{IL} = V_{IH}$	MUX, MODE[01], PSS[02], OCDS[01]	-0.4V V _{CCD} + 0.4	V V
Gain Adjustment function	GA	-0.3V, V _{CCA3} + 0.3	V
Maximum Junction Temperature	Тј	170	°C
Storage Temperature	Tstg	-65 to 150	°C
Electrostatic discharge immunity ESD Classification	ESD HBM	1000 Class 1B	V

Notes: 1. Absolute maximum ratings are limiting values (referenced to GND = 0V), to be applied individually, while other parameters are within specified operating conditions. Long exposure to maximum rating may affect device reliability.

2. All integrated circuits have to be handled with appropriate care to avoid damages due to ESD. Damage caused by inappropriate handling or storage could range from performance degradation to complete failure.

3. Maximum ratings enable active inputs with DAC powered off.

4. Maximum ratings enable floating inputs with DAC powered on.

5. DSP clock and STVF, HTVF output buffers must not be shorted to ground nor positive power supply.

3.2 Recommended Conditions of Use

Table 3-2. Recommended Conditions of Use

Parameter	Symbol	Comments	Recommended Value	Unit	Note
Positive analog supply voltage	V _{CCA5}		5.0	V	(2)(4)
Positive analog supply voltage	V _{CCA3}		3.3	V	(1)(2)(4)
Positive digital supply voltage	V _{CCD}		3.3	V	(2)(4)
Digital inputs (on each single-ended input) and IDC, SYNC, signal Port P = A, B, C, D V _{IL} V _{IH} Differential mode swing	[P0P11], [P0N P11N] IDC_P, IDC_N SYNC, SYNCN		1.075 1.425 700	V V mV _{pp}	(3)
Master clock input power level (Differential mode)	P _{CLK}		3	dBm	(3)
Control functions inputs	MUX, OCDS, PSS, MODE, PSS	V _{IL} V _{IH}	0 V _{CCD}	V V	
Gain Adjustment function	GA	Range	0 V _{CCA3}	v	
Operating Temperature Range	T _c T _j	Commercial "C" grade Industrial "V" grade	T _c > 0°C / T _j < 90°C T _c > -40°C / T _j < 110°C	°C	

Notes: 1. For low temperature it is recommended to operate at maximum analog supplies (V_{CCA3}) level.

The rise time of any power supplies (V_{CCD}, V_{CCA5}, V_{CCA3}) shall be <10ms.
 For EV12DS130A, in order to obtain the guaranteed performances and functionality, the following rules shall be followed when powering the devices (See Section 8.9 "Power Up Sequencing" on page 72)
 For EV12DS130B, no specific power up sequence nor power supplies relationships are required.

- 3. Analog output is in differential. Single-ended operation is not recommended. Guaranteed performance is only in differential configuration.
- 4. No power-down sequencing is required.

3.3 Electrical Characteristics

Values in the tables below are based on our conditions of measurement in room temperature for typical power supply ($V_{CCA5} = 5.0V$, $V_{CCA3} = 3.3V$, $V_{CCD} = 3.3V$), typical swing and in MUX4:1 otherwise specified.

Table 3-3. Electrical Characteristic

Parameter	Symbol	Min	Тур	Max	Unit	Note	Test Level ⁽²
RESOLUTION			12		bit		
POWER REQUIREMENTS						•	
Power Supply voltage							
- Analog - Analog - Digital	V _{CCA5} V _{CCA3} V _{CCD}	4.75 3.15 3.15	5 3.3 3.3	5.25 3.45 3.45	V V	(7)(8)	1
Power Supply current (4:1 MUX)							
- Analog - Analog - Digital	I _{CCA5} I _{CCA3} I _{CCD}		84 106 187	90 122 205	mA mA mA		1
Power Supply current (2:1 MUX)							
- Analog - Analog - Digital	I _{CCA5} I _{CCA3} I _{CCD}		84 106 160	90 122 177	mA mA mA		1
Power dissipation (4:1 MUX)	P _D		1.4	1.6	W		1
Power dissipation (2:1 DMUX)	P _D		1.3	1.5	W		1
DIGITAL DATA INPUTS, SYNC and IDC INPUTS							
Logic compatibility			LVDS				
Digital input voltages:							
- Differential input voltage - Common mode	V _{ID} V _{ICM}	100	350 1.25	500	mV _p V		1 1
Input capacitance from each single input to ground				2	pF		5
Differential Input resistance		80	100	120	Ω		1
CLOCK INPUTS							-
Input voltages (Differential operation swing)		0.56	1	2.24	V _{pp}		4
Power level (Differential operation)		-4	1	8	dBm	(1)	4
Common mode		2.4	2.5	2.6	v		
Input capacitance from each single input to ground (at die level)				2	pF		5
Differential Input resistance:		80	100	120	Ω		1
DSP CLOCK OUTPUT							
Logic compatibility			LVDS				
Digital output voltages:							
- Differential output voltage - Common mode	V _{OD} V _{OCM}	240	350 1.3	450	mV _p V		1

Table 3-3. Electrical Characteristics (Continued)

Parameter	Symbol	Min	Тур	Max	Unit	Note	Test Level ⁽²⁾
ANALOG OUTPUT							
Full-scale Differential output voltage (100Ω differentially terminated)		0.92	1	1.08	V _{pp}		1
Full-scale output power (differential output)		0.25	1	1.64	dBm		1
Single-ended mid-scale output voltage (50 Ω terminated)			V _{CCA5} - 0.43		V	(4)	
Output capacitance			1.5		pF		5
Output internal differential resistance		90	100	110	Ω		1
Output VSWR (using e2v evaluation board) 1.5 GHz 3 GHz 4.5 GHz			1.17 1.54 1.64				4
Output bandwidth			7		GHz		4
FUNCTIONS							
Digital functions: MODE, OCDS, PSS, MUX							
- Logic 0 - Logic 1	V _{IL} V _{IH} I _{IN}	1.6	0 V _{CCD}	0.8 150	V V μA	(6)	1
Gain Adjustment function	GA		0 V _{CCA3}				1
Digital output function (HTVF, STVF)							
Logic 0 Logic 1	V _{oL} V _{OH} I _o	_ 2.3		0.8 80	V V μA	(5) (6)	1
DC ACCURACY							
Differential Non-Linearity	DNL+		0.5	0.95	LSB		1
Differential Non-Linearity	DNL-	-0.95	-0.5		LSB		1
Integral Non-Linearity	INL+		1	3	LSB		1
Integral Non-Linearity	INL-	-3	-0.8		LSB		1
DC gain:							
 Initial gain error DC gain adjustment DC gain sensitivity to power supplies DC gain drift over temperature 		-8	0 ±11 ±2	+8 +6	% % %	(3)	1 1 1 4

Notes: 1. For use in higher Nyquist zone, it is recommended to use higher power clock within the limit.

- 2. See Section 3.6 on page 13 for explanation of test levels.
- Initial gain error corresponds to the deviation of the DC gain center value from unity gain. The DC gain adjustment (GA function) ensures that the initial gain deviation can be cancelled. The DC gain sensitivity to power supplies is given according the rule: GainSensVsSupply = |Gain@VccMin – Gain@VccMax| / Gain@Vccnom
- 4. Single-ended operation is not recommended, this line is given for better understanding of what is output by the DAC.
- 5. In order to modify the V_{OI}/V_{OH} value, potential divider could be used.
- 6. Sink or source.

- 7. Only for EV12DS130A dependency between power supplies: Within the applicable power supplies range, the following relationship shall always be satisfied $V_{CCA3} \ge V_{CCD}$, taking into account AGND and DGND planes are merged and power supplies accuracy.
- 8. Please refer Section 8.9 "Power Up Sequencing" on page 72.

3.4 AC Electrical Characteristics

Values in the tables below are based on our conditions of measurement in room temperature for typical power supply (V_{CCA5} = 5.0V, V_{CCA3} = 3.3V, V_{CCD} = 3.3V), typical swing and in MUX4:1 otherwise specified.

Parameter	Symbol	Min	Тур	Max	Unit	Note	Test level ⁽¹⁾
Single-tone Spurious Free Dynamic Range First Nyquist MUX 4:1							
Fs = 3 Gsps @ Fout = 100 MHz 0 dBFS Fs = 3 Gsps @ Fout = 400 MHz 0 dBFS	SFDR	59	68 63		dBc		1 4
							4
Fs = 3 Gsps @ Fout = 100 MHz -3 dBFS			70				4
Highest spur level First Nyquist MUX 4:1							
Fs = 3 Gsps @ Fout = 100 MHz 0 dBFS Fs = 3 Gsps @ Fout = 400 MHz 0 dBFS			-68 -59	-58	dBm		1 4
Fs = 3 Gsps @ Fout = 100 MHz −3 dBFS			-72				4
SFDR sensitivity & high spur level variation over temperature			±2		dB		4
SFDR sensitivity & high spur level variation over power supplies			±2		dB		4
Signal independent Spur (clock-related spur)							
Fc/2			-82		dBm		4
Fc/4			-85		dBm		4
Noise Power Ratio -14 dBFS peak to rms loading factor Fs = 3 Gsps 20 MHz to 900 MHz broadband pattern 25 MHz notch centered on 450 MHz	NPR		46		dB	(2)	4
Equivalent ENOB Computed from NPR figure at 3 GSps	ENOB		9.2		Bit		4
Signal to Noise Ratio Computed from NPR figure at 3 GSps	SNR		57		dB		4
DAC self noise density at constant code 0 or 4095			-163		dBm/Hz		4

Notes: 1. See Section 3.6 on page 13 for explanation of test levels.

 Figures in tables are derived from industrial screening; for practical reasons (necessity to cover also 2nd and 3rd Nyquist Zones) the balun used for industrial test is not optimum for first Nyquist performances, and results when Fout or folded low order hamonics are between DC to 400 MHz are very pessimistic. For further details please refer to Section 7.2 on page 38 for effect of the balun on performances.

Table 3-5.	AC Electrical Characteristics NRTZ Mode (First & Second Nyquist Zone)
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Parameter	Symbol	Min	Тур	Max	Unit	Note	Test level ⁽¹⁾
Single-tone Spurious Free Dynamic Range MUX4:1 Fs = 3 Gsps @ Fout = 100 MHz 0 dBFS Fs = 3 Gsps @ Fout = 700 MHz 0 dBFS Fs = 3 Gsps @ Fout = 1800 MHz 0 dBFS Fs = 3 Gsps @ Fout = 700 MHz -3 dBFS	SFDR	54	68 62 61 66		dBc		4 4 1 4
MUX2:1 Fs = 1.5 Gsps @ Fout = 700 MHz 0 dBFS		53	65				1
Highest spur level MUX4:1 Fs = 3 Gsps @ Fout = 100 MHz 0 dBFS Fs = 3 Gsps @ Fout = 700 MHz 0 dBFS Fs = 3 Gsps @ Fout = 1800 MHz 0 dBFS Fs = 3 Gsps @ Fout = 700 MHz -3 dBFS MUX2:1 Fs = 1.5 Gsps @ Fout = 700 MHz 0 dBFS			-70 -64 -67 -70 -68	-59	dBm		4 4 1 4
SFDR sensitivity & high spur level variation over temperature			±2		dB		4
SFDR sensitivity & high spur level variation over power supplies			±2		dB		4
Signal independent Spur (clock-related spur)							
Fc			-29		dBm		4
Fc/2			-80		dBm		4
Fc/4			< -80		dBm		4
DAC self noise density at constant code 0 or 4095			-149	-144	dBm/Hz		1
Noise Power Ratio –14 dBFS peak to rms loading factor Fs = 3 Gsps 20 MHz to 900 MHz broadband pattern, 25 MHz notch centered on 450 MHz	NPR	46	50.2		dB	(2)	1
Equivalent ENOB Computed from NPR figure at 3 GSps	ENOB	9.2	9.9		Bit	(2)	1
Signal to Noise Ratio Computed from NPR figure at 3 GSps	SNR	57	61.2		dB	(2)	1
Noise Power Ratio –14 dBFS peak to rms loading factor Fs = 1.5 Gsps 10 MHz to 450 MHz broadband pattern, 12.5 MHz notch centered on 225 MHz	NPR		55.7		dB	(2)	4
Equivalent ENOB Computed from NPR figure at 1.5 GSps	ENOB		10.8		Bit	(2)	4
Signal to Noise Ratio Computed from NPR figure at 1.5 GSps	SNR		66.7		dB	(2)	4

Notes: 1. See Section 3.6 on page 13 for explanation of test levels.

2. Figures in tables are derived from industrial screening; for practical reasons (necessity to cover also 2nd and 3rd Nyquist Zones) the balun used for industrial test is not optimum for first Nyquist performances, and results when Fout or folded low order hamonics are between DC to 400 MHz are very pessimistic. For further details please refer to Section 7.2 on page 38 for effect of the balun on performances.

Table 3-6.	AC Electrical Characteristics RTZ Mode (Second Nyquist Zone)
	Ac Electrical characteristics fire mode (Second Nyquist zone)

Parameter	Symbol	Min	Тур	Max	Unit	Note	Test level ⁽¹⁾
Single-tone Spurious Free Dynamic Range MUX4:1 Fs = 3 Gsps @ Fout = 1600 MHz 0 dBFS Fs = 3 Gsps @ Fout = 2900 MHz 0 dBFS	SFDR	50	60 57		dBc		1 4
Highest spur level MUX4:1 Fs = 3 Gsps @ Fout = 1600 MHz 0 dBFS Fs = 3 Gsps @ Fout = 2900 MHz 0 dBFS			-67 -66	-58	dBm		1 4
SFDR sensitivity & high spur level variation over temperature			±2		dB		4
SFDR sensitivity & high spur level variation over power supplies			±2		dB		4
Signal independent Spur (clock-related spur)							
Fc			-25		dBm		4
Fc/2			-80		dBm		4
Fc/4			< -80		dBm		4
DAC self noise density at constant code 0 or 4095			-143		dBm/Hz		4
Noise Power Ratio –14 dBFS peak to rms loading factor Fs = 3 Gsps 1520 MHz to 2200 MHz broadband pattern, 25 MHz notch centered on 1850 MHz	NPR	40	44.0		dB	(2)	1
Equivalent ENOB Computed from NPR figure at 3 GSps	ENOB	8.2	8.8		Bit	(2)	1
Signal to Noise Ratio Computed from NPR figure at 3 GSps	SNR	51	55.0		dB	(2)	1

Notes: 1. See Section 3.6 on page 13 for explanation of test levels.

2. Please refer to Section 7.2 "AC Performances" on page 38 to have detailed characterization results.

Table 3-7.	AC Electrical Characteristics RF Mode (Second and Third Nyquist Zones)
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Parameter	Symbol	Min	Тур	Max	Unit	Note	Test level ⁽¹⁾
Single-tone Spurious Free Dynamic Range 2 nd Nyquist Fs = 3 Gsps @ Fout = 1600 MHz 0 dBFS Fs = 3 Gsps @ Fout = 2900 MHz 0 dBFS	SFDR		52 60		dBc		4
3 rd Nyquist Fs = 3 Gsps @ Fout = 3800 MHz 0 dBFS Fs = 3 Gsps @ Fout = 4400 MHz 0 dBFS	1	47	53 54			(2)	4
Highest spur level 2^{nd} Nyquist Fs = 3 Gsps @ Fout =1600 MHz 0 dBFS Fs = 3 Gsps @ Fout = 2900 MHz 0 dBFS 3^{rd} Nyquist Fs = 3 Gsps @ Fout = 4400 MHz 0 dBFS			-58 -58 -62	-57	dBm		4 4
SFDR sensitivity & high spur level variation over temperature			±2		dB		4
SFDR sensitivity & high spur level variation over power supplies			±2		dB		4
Signal independent Spur (clock-related spur)							
Fc			-28		dBm		4
Fc/2			-80		dBm		4
Fc/4			< -80		dBm		4
DAC self noise density at constant code 0 or 4095			-141		dBm/Hz		4
Noise Power Ratio (2 nd Nyquist) –14 dBFS peak to rms loading factor Fs = 3 Gsps 1520 MHz to 2200 MHz broadband pattern, 25 MHz notch centered on 1850 MHz	NPR		42		dB	(2)	4
Equivalent ENOB Computed from NPR figure at 3 GSps	ENOB		8.5		Bit	(2)	4
Signal to Noise Ratio Computed from NPR figure at 3 GSps	SNR		53		dB	(2)	4
Noise Power Ratio -14 dBFS peak to rms loading factor Fs = 3 Gsps 2200 MHz to 2880 MHz broadband pattern, 25 MHz notch centered on 2550 MHz	NPR		42		dB	(2)	4
Equivalent ENOB Computed from NPR figure at 3 GSps	ENOB		8.5		Bit	(2)	4
Signal to Noise Ratio Computed from NPR figure at 3 GSps	SNR		53		dB	(2)	4

Table 3-7.	AC Electrical Characteristics RF Mode (Second and Third Nyquist Zones) (Continued)
	The Electrical characteristics in mode (Second and Third Hydrist Eones) (continued)

Parameter	Symbol	Min	Тур	Max	Unit	Note	Test level ⁽¹⁾
Noise Power Ratio -14 dBFS peak to rms loading factor Fs = 3 Gsps 3050 MHz to 3700 MHz broadband pattern, 25 MHz notch centered on 3375 MHz	NPR	39	40		dB	(2)	1
Equivalent ENOB Computed from NPR figure at 3 GSps	ENOB	8	8.2		Bit	(2)	1
Signal to Noise Ratio Computed from NPR figure at 3 GSps	SNR	50	51		dB	(2)	1

Notes: 1. See Section 3.6 on page 13 for explanation of test levels.

 Figures in tables are derived from industrial screening without any correction to take in account the balun effect, but for practical reasons (necessity to cover also 2nd and 3rd Nyquist Zones) the balun used for industrial test is not optimum for first Nyquist performances, and results when Fout or folded low order hamonics are between DC to 400 MHz are very pessimistic.

3.5 Timing Characteristics and Switching Performances

Table 3-8. Timing Characteristics and Switching Performances

Parameter	Symbol	Min	Тур	Max	Unit	Note	Test level ⁽¹
SWITCHING PERFORMANCE AND CHARACTERISTICS	;						
Operating clock frequency							
4:1 MUX mode		300		3000	MHz		4
2:1 MUX mode		300		1500			
TIMING CHARACTERISTICS							
Analog output rise/fall time	T _{OR} T _{OF}			60	ps	(2)	4
Data Tsetup (Fc = 3 Gsps)		250			ps	(3)	4
Data Thold (Fc = 3 Gsps)		100			ps	(3)	4
Max Input data rate (Mux 4:1)		75		750	MSps		4
Max Input data rate (Mux 2:1)		150		750	MSps		4
Master clock input jitter				100	fs rms	(4)	5
DSP clock phase tuning steps			0.5		Clock period		5
Master clock to DSP, DSPN delay	TDSP		1.6		ns		4
SYNC forbidden area lower bound (Fc = 3 Gsps)	T ₁		350		ps	(5)(6)	4
SYNC forbidden area upper bound (Fc = 3 Gsps)	T ₂		330		ps	(5)(6)	4
SYNC to DSP, DSPN MUX 2:1 MUX4:1			880 1600		ps		4
Data Pipeline Delay MUX4:1 MUX2:1	TPD		3.5 3.5		Clock period		4
Data Output Delay	TOD		160		ps		4

- Notes: 1. See Section 3.6 on page 13 for explanation of the test level.
 - 2. Analog output rise/fall time measured from 20% to 80% of a full scale jump, after probe de-embedding.
 - 3. Exclusive of period (pp) jitter on Data. Setup and hold time for DATA at input relative to DSP clock at output of the component, at PSS = 000; also applicable for IDC signal.
 - 4. Master clock input jitter defined over 5 GHz bandwidth.
 - 5. The SYNC signal is captured on the falling edge of the master clock and is active high. Refer to Figure 3-3.
 - 6. For EV12DS130A, please refer to erratasheet 1125

Figure 3-1. Timing Diagram for 4:1 MUX Principle of Operation OCDS[00]

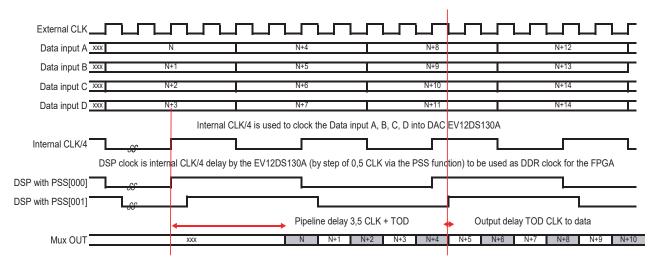
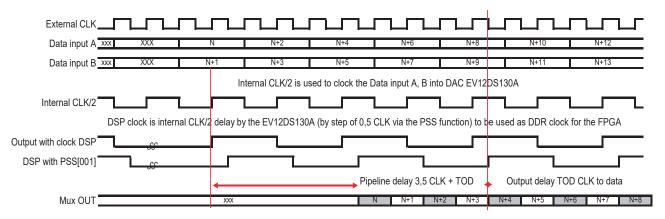
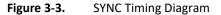
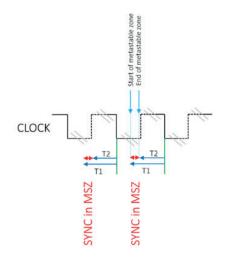


Figure 3-2. Timing Diagram for 2:1 MUX Principle of Operation OCDS[00]







Please refer to Section 5.8 "Synchronization functions for multi-DAC operation" on page 26.

3.6 Explanation of Test Levels

1	100% production tested at +25°C ⁽¹⁾
2	100% production tested at +25°C ⁽¹⁾ , and sample tested at specified temperatures.
3	Sample tested only at specified temperatures
4	Parameter is guaranteed by design and/or characterization testing (thermal steady-state conditions at specified temperature)
5	Parameter value is guaranteed by design
6	100% production tested over specified temperature range (for Space/Mil grade ⁽²⁾)

Only MIN and MAX values are guaranteed.

- Notes: 1. Unless otherwise specified.
 - 2. If applicable, please refer to "Ordering Information"

3.7 Digital Input Coding Table

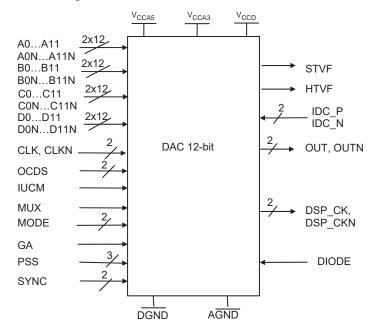
Table 3-9.	Coding Table (Theorical values)	
	Digital output msblsb	Differential analog output
	0000000000	–500 mV
	01000000000	–250 mV
	01100000000	–125 mV
	01111111111	–0.122 mV
	10000000000	0.122 mV
	10100000000	+125 mV
	11000000000	+250 mV
	11111111111	+500 mV

4. DEFINITION OF TERMS

Abbreviation	Term	Definition
(Fs max)	Maximum conversion Frequency	Maximum conversion frequency
(Fs min)	Minimum conversion frequency	Minimum conversion Frequency
(SFDR)	Spurious free dynamic range	Ratio expressed in dB of the RMS signal amplitude, set at Full Scale, to the RMS value of the highest spectral component (peak spurious spectral component). The peak spurious component may or may not be a harmonic. It may be reported in dB (i.e., related to converter 0 dB Full Scale), or in dBc (i.e, related to input signal level).
(HSL)	High Spur Level	Power of highest spurious spectral component expressed in dBm.
(ENOB)	Effective Number Of Bits	ENOB is determinated from NPR measurement with the formula: ENOB = (NPR _[dB] + ILF _[dB] I - 3 - 1.76) / 6.02 Where LF "Loading factor" is the ratio between the Gaussian noise standard deviation versus amplitude full scale.
(SNR)	Signal to noise ratio	SNR is determinated from NPR measurement with the formula: $SNR_{[dB]} = NPR_{[dB]} + ILF_{[dB]}I - 3$ Where LF "Loading factor" is the ratio between the Gaussian noise standard deviation versus amplitude full scale.
(DNL)	Differential non linearity	The Differential Non Linearity for an given code i is the difference between the measured step size of code i and the ideal LSB step size. DNL (i) is expressed in LSBs. DNL is the maximum value of all DNL (i). DNL error specification of less than 1 LSB guarantees that there are no missing point and that the transfer function is monotonic.
(INL)	Integral non linearity	The Integral Non Linearity for a given code i is the difference between the measured voltage at which the transition occurs and the ideal value of this transition. INL (i) is expressed in LSBs, and is the maximum value of all INL (i)
(TPD/TOD)	Output delay	The analog output propagation delay measured between the rising edge of the differential CLK, CLKN clock input (zero crossing point) and the zero crossing point of a full-scale analog output voltage step. TPD corresponds to the pipeline delay plus an internal propagation delay (TOD) including package access propagation delay and internal (on-chip) delays such as clock input buffers and DAC conversion time.
(NPR)	Noise Power Ratio	The NPR is measured to characterize the DAC performance in response to broad bandwidth signals. When applying a notch-filtered broadband white-noise pattern at the input to the DAC under test, the Noise Power Ratio is defined as the ratio of the average noise measured on the shoulder of the notch and inside the notch on the same integration bandwidth.
(VSWR)	Voltage Standing Wave Ratio	The VSWR corresponds to the insertion loss linked to power reflection. For example a VSWR of 1:2 corresponds to a 20dB return loss (ie. 99% power transmitted and 1% reflected).
(IUCM)	Input under clocking mode	The IUCM principle is to apply a selectable division ratio between DAC section clock and the MUX section clock.
(PSS)	Phase Shift Select	The Phase Shift Select function allow to tune the phase of the DSPclock.
(OCDS)	Output Clock Division Selectt	It allows to divide the DSPclock frequency by the OCDS coded value factor
(NRZ)	Non Return to Zero mode	Non Return to Zero mode on analog output
(RF)	Radio Frequency mode	RF mode on analog output
(RTZ)	Return to zero	Return to zero mode on analog output
(NRTZ)	Narrow return to zero	Narrow return to zero mode on analog output

5. FUNCTIONAL DESCRIPTION

Figure 5-1.	DAC Functional Diagram
-------------	------------------------



Name	Function	Name	Function
V _{CCD}	3.3V Digital Power Supply	CLK	In-phase Master clock
V _{CCA5}	5.0V Analog Power Supply	CLKN	Inverted phase Master clock
V _{CCA3}	3.3V Analog Power Supply	DSP_CK	In-phase Output clock
DGND	Digital Ground	DSP_CKN	Inverted phase Output clock
AGND	Analog ground (for analog supply reference)	PSS[02]	Phase shift select
A[110]	In-phase digital input Port A	GA	Gain Adjust
A[110]N	Inverted phase digital input Port A	MUX	Multiplexer Selection
B[110]	In-phase digital input Port B	MODE[01]	DAC Mode: NRZ, RTZ, NRTZ, RF
B[110]N	Inverted phase digital input Port B	STVF	Setup time Violation flag
C[110]	In-phase digital input Port C	HTVF	Hold time Violation flag
C[110]N	Inverted phase digital input Port C	IDC_P, IDC_N	Input data check
D[110]	In-phase digital input Port D	OCDS[01]	Output Clock Division factor Selection
D[110]N	Inverted phase digital input Port D	Diode	Diode for temperature monitoring
OUT	In-phase analog output	SYNC/SYNCN	Synchronization signal (Active High)
OUTN	Inverted phase analog output		

5.1 DSP Output Clock

The DSP output clock DSP, DSPN is an LVDS signal which is used to synchronize the FPGA generating the digital patterns with the DAC sampling clock.

The DSP clock frequency is a fraction of the sampling clock frequency. The division factor depends on OCDS settings. The DSP clock frequency is equal to (sampling frequency / [2N*X]) where N is the MUX ratio and X is the output clock division factor, determined by OCDS[0..1] bits.

For example, in a 4:1 MUX ratio application with a sampling clock of 3 GHz and OCDS set to "00" (ie. Factor of 1), the input data rate is 750 MSps and the DSP clock frequency is 375 MHz.

This DSP clock is used in the FPGA to control the digital data sequencing. Its phase can be adjusted using the PSS[2:0] bits (refer to Section 5.4 on page 21) in order to ensure a proper synchronization between the data coming to the DAC and the sampling clock.

The HTVF and STVF bits should be used to check whether the timing between the FPGA and the DAC is correct. HTVF and STVF bits will indicate whether the DAC and FPGA are aligned or not. PSS bits should then be used to shift the DSP clock and thus the input data of the DAC, so that a correct timing is achieved between the FPGA and the DAC.

Important note: Maximum supported sampling frequency when using DSP to clock digital data is 2.1 Gsps on EV12DS130B. Please refer to application note AN1141 to use EV12DS130B at sampling frequency beyond 2.1 GHz.

5.2 Multiplexer

Two multiplexer ratio are allowed:

- 4:1 which allows operation at full sampling rate (ie. 3 GHz)
- 2:1 which can only be used up to 1.5 GHz sampling rate

	Label	Value	Description
	MUX	0	4:1 mode
		1	2:1 mode

In 2:1 MUX ratio, the unused data ports (ports C and D) can be left open.

5.3 MODE Function

Label	Value	Description	Default Setting (Not Connected)
MODE[1:0]	00	NRZ mode	
	01	Narrow RTZ (a.k.a. NRTZ) mode	11
	10	RTZ Mode (50%)	RF mode
	11	RF mode	

The MODE function allows choosing between NRZ, NRTZ, RTZ and RF functions. NRZ and narrow RTZ should be chosen for use in 1st Nyquist zone while RTZ should be chosen for use in 2nd and RF for 3rd Nyquist zones.

Theory of operation: see following subsections for time domain waveform of the different modes.

Ideal equations describing max available Pout for frequency domain in the four modes are given hereafter, with X = normalized output frequency (that is Fout/Fclock, edges of Nyquist zones are then at X = $0 \frac{1}{2} \frac{1}{3} \frac{2}{2} \dots$). Due to limited bandwidth, an extra term must be added to take in account a first order low pass filter.

NRZ mode:

$$Pout(X) = 20 \cdot \log_{10} \cdot \left[\frac{|k \cdot sinc(k \cdot \pi \cdot X)|}{0.893}\right]$$

where sinc(x) = sin(x)/x, and k = 1

NRTZ mode:

$$\text{Pout}(X) = 20 \cdot \log_{10} \cdot \left[\frac{|k \cdot \text{sinc}(k \cdot \pi \cdot X)|}{0.893} \right] \qquad k = \frac{\text{Tclk} - \text{T}\tau}{\text{Tclk}}$$

where $T\tau$ is width of reshaping pulse, $T\tau$ is about 75ps.

RTZ mode:

$$Pout(X) = 20 \cdot \log_{10} \cdot \left[\frac{|k \cdot \operatorname{sinc}(k \cdot \pi \cdot X)|}{0.893} \right]$$

where k is the duty cycle of the clock presented at the DAC input, please note that due to phase mismatch in balun used to convert single ended clock to differential clock the first zero may move around the limit of the 4^{th} and the 5^{th} Nyquist zones. Ideally k = 1/2.

RF mode:

$$Pout(X) = 20 \cdot \log_{10} \cdot \left[\frac{\left| k \cdot \operatorname{sinc} \left(\frac{k \cdot \pi \cdot X}{2} \right) \cdot \operatorname{sin} \left(\frac{k \cdot \pi \cdot X}{2} \right) \right|}{0.893} \right]$$

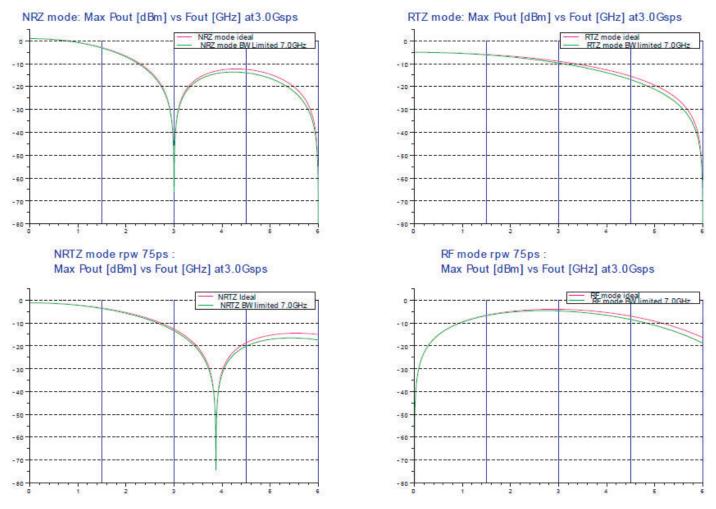
where k is as per in NRTZ mode.

As a consequence:

- NRZ mode offers max power for 1st Nyquist operation
- RTZ mode offers slow roll off for 2nd Nyquist or 3rd Nyquist operation
- RF mode offers maximum power over 2nd and 3rd Nyquist operation
- NRTZ mode offers optimum power over full 1st and first half of 2nd Nyquist zones. This is the most relevant in term of performance for operation over 1st and beginning of 2nd Nyquist zone. Depending on the sampling rate the zero of transmission moves in the 3rd Nyquist zone from begin to end when sampling rate increases.

Note in the two following figures: Pink line is ideal equation's result, and green line includes a first order 6 GHz cut-off low pass filter to take into account finite bandwidth effect due to die and package.

Figure 5-2. Max Available Pout[dBm] at Nominal Gain vs Fout[GHz] in the Four Output Modes at 3 Gsps, over four Nyquist Zones, Computed for $T\tau = 75$ ps.



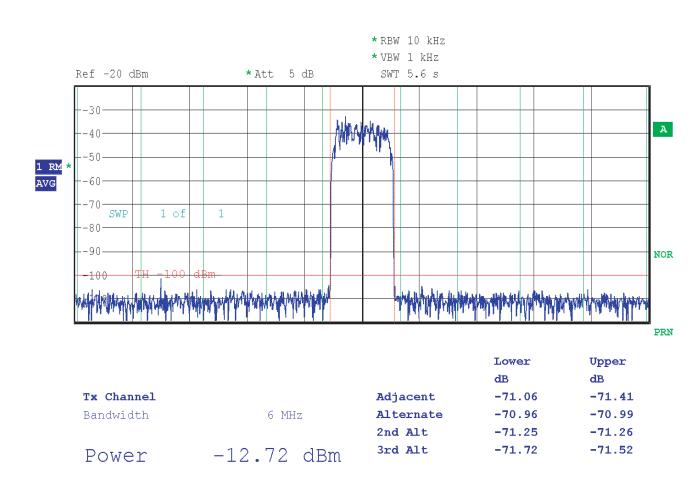
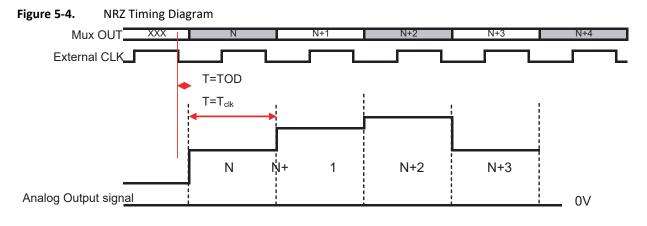


Figure 5-3.Max available Pout[dBm] at Nominal Gain vs Fout[GHz] in the Four Output Modes at 2 Gsps, over four
Nyquist Zones, Computed for $T\tau = 75$ ps

5.3.1 NRZ Output Mode

This mode does not allow for operation in the 2nd Nyquist zone because of the Sinx/x notch.

The advantage is that it gives good results at the beginning of the 1st Nyquist zone (less attenuation than in RTZ architecture), it removes the parasitic spur at the clock frequency (in differential).

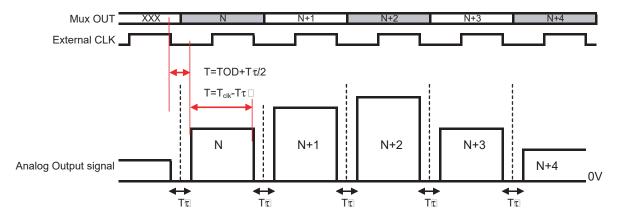


5.3.2 Narrow RTZ Mode (NRTZ Mode)

This mode has the following advantages:

- Optimized power in 1st Nyquist zone
- Extended dynamic through elimination of noise on transition edges
- Improved spectral purity (see Section 7.2.3 on page 46)
- Trade off between NRZ and RTZ

Figure 5-5. Narrow RTZ Timing Diagram



Note: $T\tau$ is independent of Fclock.

5.3.3 RTZ Mode

The advantage of the RTZ mode is to enable the operation in the 2nd zone but the drawback is clearly to attenuate more the signal in the first Nyquist zone.

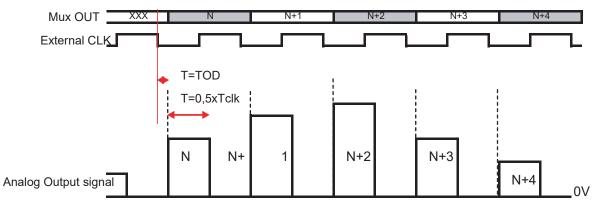
Advantages:

- Extended roll off of sinc
- Extended dynamic through elimination of hazardous transitions

Weakness:

• By construction clock spur at Fs.

Figure 5-6. RTZ Timing Diagram



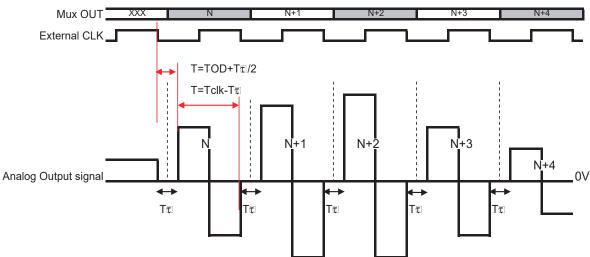
5.3.4 RF Mode

RF mode is optimal for operation at high output frequency, since the decay with frequency occurs at higher frequency than for RTZ. Unlike NRZ or RTZ modes, RF mode presents a notch at DC and 2N*Fs, and minimum attenuation for Fout = Fs.

Advantages:

- Optimized for 2nd and 3rd Nyquist operation
- Extended dynamic range through elimination of hazardous transitions.
- Clock spur pushed to 2.Fs

Figure 5-7. RF Timing Diagram



Note: The central transition is not hazardous but its elimination allows to push clock spur to 2.Fs $T\tau$ is independent of Fclock.

5.4 PSS (Phase Shift Select Function)

It is possible to adjust the timings between the sampling clock and the DSP output clock (which frequency is given by the following formula: Sampling clock / 2NX where N is the MUX ratio, X the output clock division factor).

The DSP clock output phase can be tuned over a range of 3.5 input clock cycles (7 steps of half a clock cycle) in addition to the intrinsic propagation delay between the DSP clock (DSP, DSPN) and the sampling clock (CLK, CLKN).

Three bits are provided for the phase shift function: PSS[2:0].

By setting these 3 bits to 0 or 1, one can add a delay on the DSP clock in order to properly synchronize the input data of the DAC and the sampling clock (the DSP clock should be applied to the FPGA and should be used to clock the DAC digital input data).

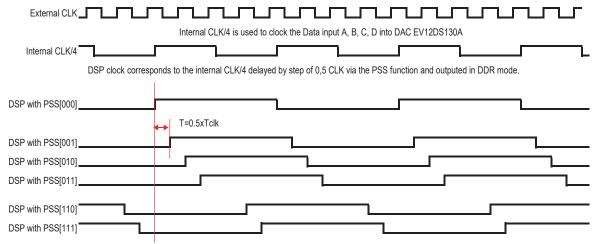
Label	Value	Description			
	000	No additional delay on DSP clock			
	001	0.5 input clock cycle delay on DSP clock			
	010	1 input clock cycle delay on DSP clock			
	011 1.5 input clock cycle delay on DSP clock				
PSS[2:0]	100	2 input clock cycle delay on DSP clock			
	101	2.5 input clock cycle delay on DSP clock			
	110	3 input clock cycle delay on DSP clock			
	111	3.5 input clock cycle delay on DSP clock			

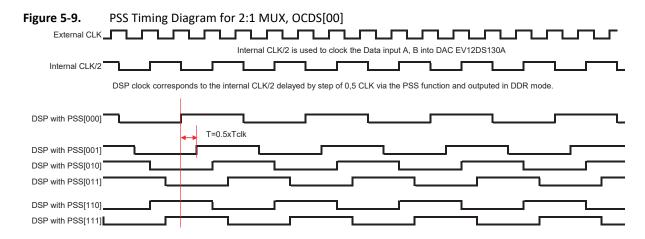
Table 5-2. PSS Coding Table

In order to determine how much delay needs to be added on the DSP clock to ensure the synchronization between the input data and the sampling clock within the DAC, the HTVF and STVF bits should be monitored. Refer to Section 5.6 on page 24.

Note: In MUX 4:1 mode the 8 settings are relevant, in MUX 2:1 only the four first settings are relevant since the four last ones will yield exactly the same results.







5.5 Output Clock Division Select Function

It is possible to change the DSP clock internal division factor from 1 to 2 with respect to the sampling clock/2N where N is the MUX ratio. This is possible via the OCDS "Output Clock Division Select" bits.

OCDS is used to obtain a synchronization clock for the FPGA slow enough to allow the FPGA to operate with no further internal division of this clock, thus its internal phase is determined by the DSP clock phase. This is useful in a system with multiple DACs and multiple FPGAs to guarantee deterministic phase relationship between the FPGAs after a synchronization of all the DACs.

Table 5-3.	OCDS[1:0] Coding Table
------------	------------------------

	0000[1:0] 00	
Label	Value	Description
	00	DSP clock frequency is equal to the sampling clock divided by 2N
00000 [1.0]	01	DSP clock frequency is equal to the sampling clock divided by 2N*2
OCDS [1:0]	10	Not allowed
	11	Not allowed

Figure 5-10. OCDS Timing Diagram for 4:1 MUX

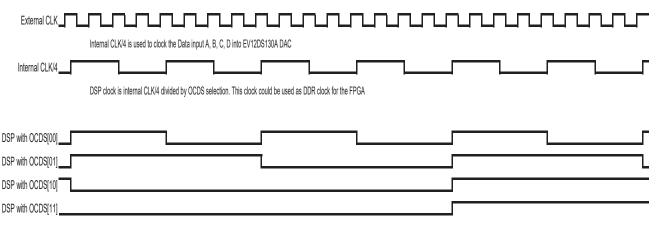
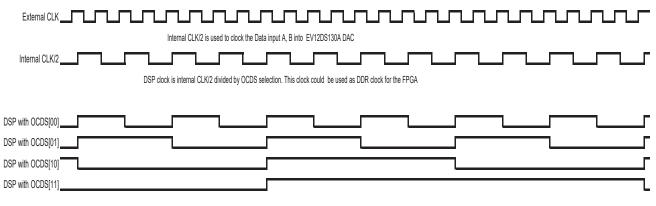


Figure 5-11. OCDS Timing Diagram for 2:1 MUX



5.6 Synchronization FPGA-DAC: IDC_P, IDC_N, HTVF and STVF Functions

IDC_P, IDC_N: Input Data check function (LVDS signal).

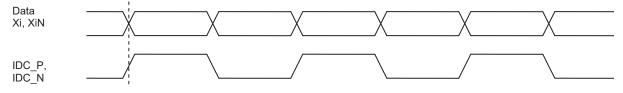
HTVF: Hold Time Violation Flag. (cmos3.3V signal)

STVF: Setup Time Violation Flag. (cmos3.3V signal)

IDC signal is toggling at each cycle synchronously with other data bits. It should be considered as a DAC input data that toggles at each cycle.

This signal should be generated by the FPGA in order for the DAC to check in real-time if the timings between the FPGA and the DAC are correct.

Figure 5-12. IDC Timing vs Data Input



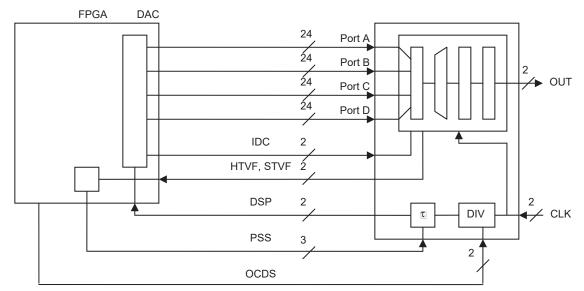
The information on the timings is then given by HTVF, STVF signals (flags).

Table 5-4.	HTVF, STVF Coding Table
------------	-------------------------

Label	Value Description			
	0	SYNCHRO OK		
HTVF	1	Data Hold time violation detected		
GT) (5	0	SYNCHRO OK		
STVF	1	Data Setup time violation detected		

During monitoring STVF indicates setup time of data violation (Low -> OK, High -> Violation), HTVF indicates hold time of data violation (Low -> OK, High -> Violation).

Figure 5-13. FPGA to DAC Synoptic



Principle of Operation:

The Input Data Check pair (IDC_P, IDC_N) will be sampled three times with half a master clock period shift (the second sample being synchronous with all the data sampling instant), these three samples will be compared, and depending on the results of the comparison a violation may be signalled.

- Violation of setup time -> STVF is high level
- Violation of hold time -> HTVF is high level

In case of violation of timing (setup or hold) the user has two solutions:

- Shift phase in the FPGA PLL (if this functionality is available in FPGA) for changing the internal timing of DATA and Data Check signal inside FPGA.
- Shift the DSP clock timing (Output clock of the DAC which can be used for FPGA synchronization refer to Section 5.4 on page 21), in this case this shift also shift the internal timing of FPGA clock.
- Note: When used, it should be routed as the data signals (same layout rules and same length). if not used, it should be driven to an LVDS low or high level.

For further details, refer to application note AN1087.

5.7 OCDS, MUX Combinations Summary

Table 5-5.	OCDS, MUX, PSS Combinations Summary
------------	-------------------------------------

MU	Х		OCDS PSS Range		Data Rate	Comments
0		00	DSP clock division factor 8			
0		01	DSP clock division factor 16		5-14	Refer to
0	4:1	10	Not allowed	0 to 7/(2Fs) by 1/(2Fs) steps	Fs/4	Section 5.5
0		11	Not allowed			

				1		
М	UX		OCDS	PSS Range	Data Rate	Comments
1		00	DSP clock division factor 4			
1		01	DSP clock division factor 8		5 /0	Refer to
1	2:1	10	Not allowed	0 to 7/(2Fs) by 1/(2Fs) steps	Fs/2	Section 5.5
1		11	Not allowed			

 Table 5-5.
 OCDS, MUX, PSS Combinations Summary

Note: Behaviour according to MUX, OCDS and PSS combination is independent of output mode (MODE).

5.8 Synchronization functions for multi-DAC operation

In order to synchronize the timings, a SYNC operation can be generated.

After the application of the SYNC signal the DSP clock from the DAC will stop for a period and after a constant and known time the DSP clock will start up again.

There are two SYNC functions integrated in this DAC:

- a power up reset, which is triggered by the power supplies if the dedicated power up sequence is applied V_{CCD} => V_{CCA3} => V_{CCA5};
- External SYNC pulse applied on (SYNC, SYNCN).

The external SYNC is LVDS compatible (same buffer as for the digital input data). It is active high.

Depending on the settings for OCDS, PSS and also the MUX ratio the width of the SYNC pulse must be greater than a certain number of external clock pulses. It is also necessary that the sync pulse be synchronized with the system clock and is an integer number of clock pulses. See application note (ref 1087) for further details.

Figure 5-14. Reset Timing Diagram (4:1 MUX)

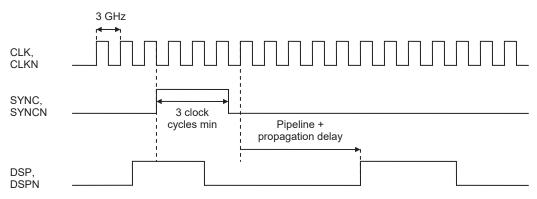
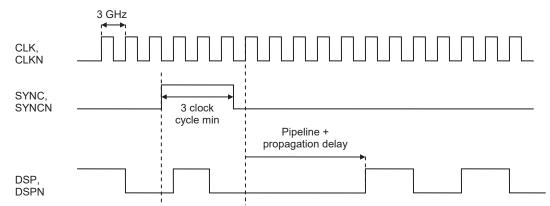


Figure 5-15. Reset Timing Diagram (2:1 MUX)



Important note:

For EV12DS130A:

- See erratasheet (ref 1125) for SYNC condition of use.
- SYNC, SYNCN pins have to be driven.

For EV12DS130B:

- SYNC, SYNCN pins can be left floating if unused.
- No specific timing constraints (other than T1 and T2) are required.

5.9 Gain Adjust GA Function

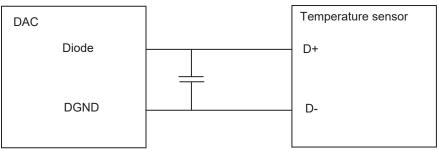
This function allows to adjust the internal gain of the DAC to cancel the initial gain deviation. The gain of the DAC can be adjusted by $\pm 11\%$ by tuning the voltage applied on GA by varying GA potential from 0 to V_{CCA3}.

GA max is given for GA = 0 and GA min for GA = V $_{CCA3}$

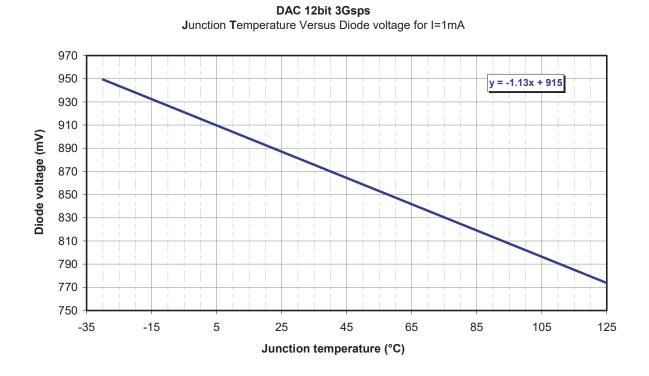
5.10 Diode Function

A diode is available to monitor the die junction temperature of the DAC. For the measurement of die junction temperature, you may use a temperature sensor.





In characterization measurement a current of 1 mA is applied on the DIODE pin. The voltage across the DIODE pin and the DGND pin gives the junction temperature using the intrinsic diode characteristics below Figure 5-17.





6. PIN DESCRIPTION

	1	2	3	4	5	6	7	8	9	10	11	12	13	14	
А	DGND	B5	B6	B6N	B9	B9N	B11	C11	C9N	C9	C6N	C6	C5	DGND	А
в	B3	В4	B5N	B7	B8	B10	B11N	C11N	C10	C8	C7	C5N	C4	C3	в
с	B1N	B3N	B4N	B7N	B8N	B10N	DGND	DGND	C10N	C8N	C7N	C4N	CЗN	C1N	С
D	B1	B2	B2N	DGND	DGND	VCCD	VCCD	VCCD	VCCD	DGND	DGND	C2N	C2	C1	D
E	A10N	BO	BON	DGND	DGND	VCCD	VCCD	VCCD	VCCD	DGND	DGND	CON	CO	D10N	E
F	A10	A11	A11N	VCCD	VCCD	AGND	AGND	AGND	AGND	VCCD	VCCD	D11N	D11	D10	F
G	A8	A8N	A9	A9N	DGND	AGND	AGND	AGND	AGND	DGND	D9N	D9	D8N	D8	G
Н	A6	A6N	A7	A7N	DGND	AGND	AGND	AGND	AGND	DGND	D7N	D7	D6N	D6	H
J	АЗN	A5	A5N	VCCA3	VCCA3	AGND	AGND	AGND	AGND	VCCA3	VCCA3	D5N	D5	D3N	J
к	A3	A4	A4N	DGND	DGND	AGND	VCCA5	VCCA5	AGND	DGND	DGND	D4N	D4	D3	к
L	A1N	A2	A2N	DGND	Diode	VCCA5	VCCA5	VCCA5	VCCA5	DGND	MUX	D2N	D2	D1N	L
M	A1	AON	GA	HTVF	STVF	VCCA5	VCCA5	AGND	AGND	MODEO	MODE1	PSS2	DON	D1	М
N	AO	DSPN	IDC_P	SYNCN	CLKN	AGND	AGND	AGND	AGND	AGND	AGND	OCDS1	OCDSO	DO	N
Р	DGND	DSP	IDC_N	SYNC	CLK	AGND	AGND	AGND	OUT	OUTN	AGND	PSSO	PSS1	DGND	Р
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	

Figure 6-1. Pinout View fpBGA196 (Top View)

Table 6-1.Pinout Table fpBGA196

Signal name	Pin number	Description	Direction	Equivalent Simplified schematics					
Power Supplies	Power Supplies								
V _{CCA5}	K7, K8, L6, L7, L8, L9, M6, M7	5V analogue power supplies Referenced to AGND	N/A						
V _{CCA3}	J4, J5, J10, J11	3.3V analogue power supply Referenced to AGND	N/A						
V _{CCD}	D6, D7, D8, D9, E6, E7, E8, E9, F4, F5, F10, F11	3.3V digital power supply Referenced to DGND	N/A						
AGND	F6, F7, F8, F9, G6, G7, G8, G9, H6, H7, H8, H9, J6, J7, J8, J9, K6, K9, M8, M9, N6, N7, N8, N9, N10, N11, P6, P7, P8, P11	Analog Ground	N/A						

able 6-1. Pinout Table fpBGA196 (Continued)							
Signal name	Pin number	Description	Direction	Equivalent Simplified schematics			
DGND	A1, A14, C7, C8, D4, D5, D10, D11, E4, E5, E10, E11, G5, G10, H5, H10, K4, K5, K10, K11, L4, L10, P1, P14	Digital Ground	N/A				
Clock Signals	1		1	L			
CLK, CLKN	P5, N5	Master sampling clock input (differential) with internal common mode It should be driven in AC coupling. Equivalent internal differential 100Ω input resistor.	I	CLKN 50Ω 2.5V CLK 50Ω 3.75 pF AGND			
DSP, DSPN	P2, N2	Output clock (in-phase and inverted phase	ο	3.3V DSP, DSPN DSPN 145Ω DGND			
Analog Output	Signal						
OUT, OUTN	P9, P10	In phase and Inverted phase analogue output signal (differential termination required)	ο	VCCA5 50Ω OUT OUT OUTN Current Switches and sources AGND			

Table 6-1. Pinout Table fpBGA196 (Continued)

Signal name	Pin number	Description	Direction	Equivalent Simplified schematics
Digital Input Si	gnals			
A0, A0N A1, A1N A2, A2N A3, A3N A4, A4N A5, A5N A6, A6N A7, A7N A8, A8N A9, A9N A10, A10N A11, A11N	N1, M2 M1, L1 L2, L3 K1, J1 K2, K3 J2, J3 H1, H2 H3, H4 G1, G2 G3, G4 F1, E1 F2, F3	In-phase, inverted phase Digital input Port A Data A0, A0N is the LSB Data A11, A11N is the MSB	1	50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω
BO, BON B1, B1N B2, B2N B3, B3N B4, B4N B5, B5N B6, B6N B7, B7N B8, B8N B9, B9N B10, B10N B11, B11N	E2, E3 D1, C1 D2, D3 B1, C2 B2, C3 A2, B3 A3, A4 B4, C4 B5, C5 A5, A6 B6, C6 A7, B7	In-phase, inverted phase Digital input Port B Data B0, B0N is the LSB Data B11, B11N is the MSB	I	1nN 50Ω 50Ω 3.75 pF DGND
C0, C0N C1, C1N C2, C2N C3, C3N C4, C4N C5, C5N C6, C6N C7, C7N C8, C8N C9, C9N C10, C10N C11, C11N	E13, E12 D14, C14 D13, D12 B14, C13 B13, C12 A13, B12 A12, A11 B11, C11 B10, C10 A10, A9 B9, C9 A8, B8	In-phase, inverted phase Digital input Port C Data C0, C0N is the LSB Data C11, C11N is the MSB	1	50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω

Table 6-1.Pinout Table fpBGA196 (Continued)

Signal name	Pin number	Description	Direction	Equivalent Simplified schematics
D0, D0N D1, D1N D2, D2N D3, D3N D4, D4N D5, D5N D6, D6N D7, D7N D8, D8N D9, D9N D10, D10N D11, D11N	N14, M13 M14, L14 L13, L12 K14, J14 K13, K12 J13, J12 H14, H13 H12, H11 G14, G13 G12, G11 F14, E14 F13, F12	In-phase, inverted phase Digital input Port D Data D0, D0N is the LSB Data D11, D11N is the MSB	I	50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω 50Ω
Control Signals				
HTVF	M4	Hold time violation flag	0	VCCD 100Ω 20Ω HTVF 400Ω DGND
STVF	M5	Setup time violation flag	0	VDD 100Ω 20Ω STVF 400Ω DGND

Table 6-1.Pinout Table fpBGA196 (Continued)

Signal name	Pin number	Description	Direction	Equivalent Simplified schematics
IDC_P, IDC_N	N3, P3	Input data check	I	50Ω 50Ω 3.75 pF DGND
PSS0 PSS1 PSS2	P12 P13 M12	Phase Shift Select (PSS2 is the MSB)	I	PSS0, PSS1, PSS2 200Ω 33 kΩ DGND
MODE0 MODE1	M10 M11	DAC Mode selection bits	Ι	MODE0 MODE1 20 kΩ 33 kΩ DGND

Table 6-1.Pinout Table fpBGA196 (Continued)

Signal name	Pin number	Description	Direction	Equivalent Simplified schematics
MUX	L11	MUX selection	I	MUX 200Ω 33 kΩ DGND
OCDS0 OCDS1	N13 N12	Output Clock Division Select = these bits allow to select the clock division factor applied on the DSP, DSPN signal.	I	OCDS0, OCDS1 200Ω 33 kΩ DGND

Table 6-1.Pinout Table fpBGA196 (Continued)

Signal name	Pin number	Description	Direction	Equivalent Simplified schematics
SYNC, SYNCN	P4, N4	In phase and Inverted phase reset signal	I	InN 50Ω
GA	МЗ	Gain adjust	1	GA 1 kΩ 300Ω 2.5 kΩ 2.5 kΩ 2.5 kΩ 4 pF AGND
Diode	L5	Diode for die junction temperature monitoring	I	Diode

Table 6-1.Pinout Table fpBGA196 (Continued)

7. CHARACTERIZATION RESULTS

Unless otherwise specified results are given at room temperature (Tj \sim 60°C), nominal power supply, in 4:1 MUX mode, gain at nominal setting.

7.1 Static Performances

7.1.1 DC Gain Characterization

Figure 7-1. DAC DC Gain vs Gain Adjust (Measured in NRZ Mode)

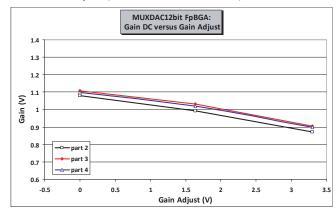
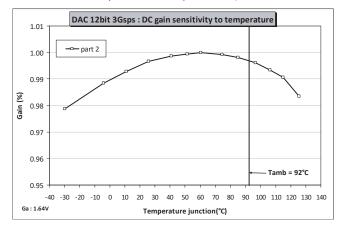
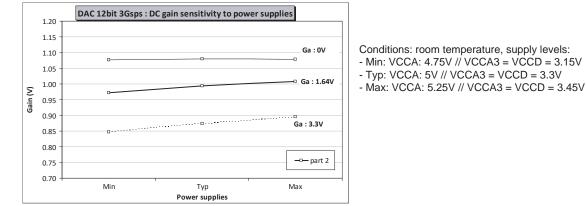


Figure 7-2. DAC DC Gain Drift from Unity Gain vs Temperature (Measured in NRZ Mode)







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7.1.2 Static Linearity

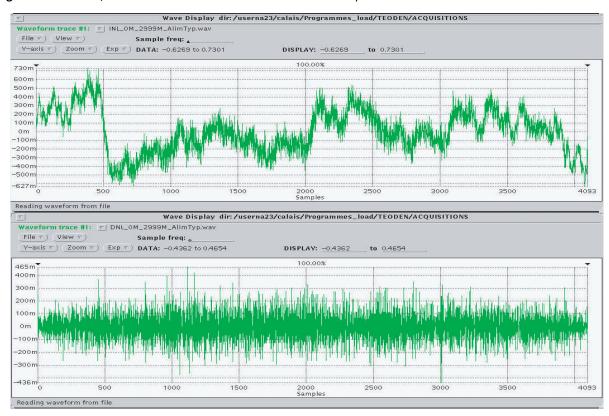


Figure 7-4. INL/DNL Measurement at Fout = 100 kHz and 3 Gsps

INL reflects a true 12 bit DAC.

Low DNL values reflect a strictly monotonous 12 bit DAC.

7.2 AC Performances

7.2.1 Available Output Power vs Fout.

The following plots summarize characterization results, for a Fout sweep from 98 MHz to 4498 MHz (step 100 MHz).

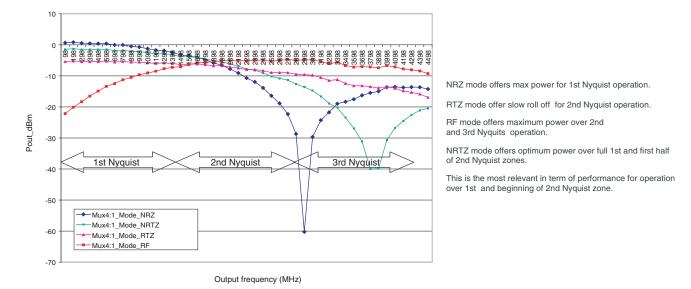
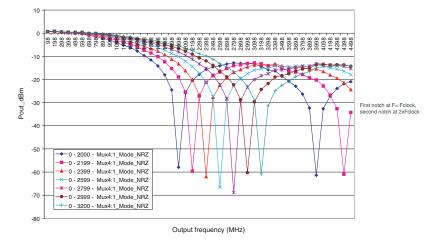


Figure 7-5. Available Pout vs Fout from 98 MHz to 4498 MHz in the 4 Output Modes at 3 Gsps

Figure 7-6. Available Pout vs Fout from 98 MHz to 4498 MHz and from 2 Gsps to 3.2 Gsps in NRZ Mode



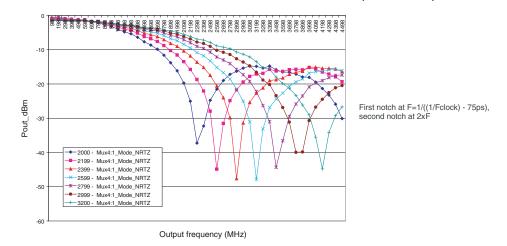
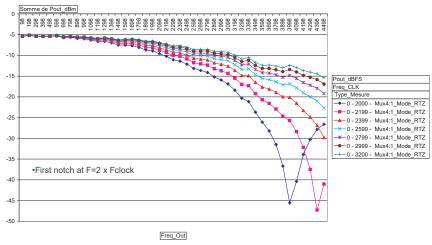
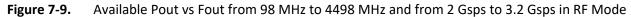
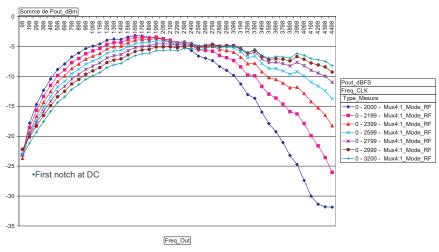


Figure 7-7. Available Pout vs Fout from 98 MHz to 4498 MHz and from 2 Gsps to 3.2 Gsps in NRTZ Mode

Figure 7-8. Available Pout vs Fout from 98 MHz to 4498 MHz and from 2 Gsps to 3.2 Gsps in RTZ Mode



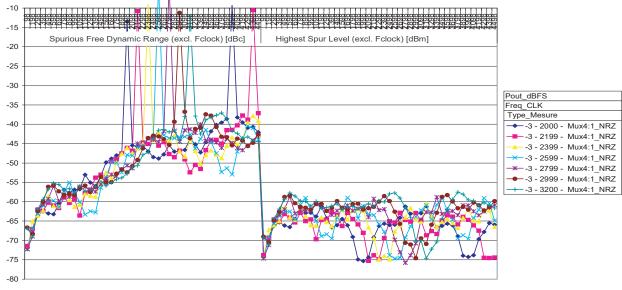




7.2.2 Single Tone Measurements

The following plots summarize characterization results in MUX4:1 mode, for an Fout sweep from 98MHzto4498MHz(step100MHz).The left side of the plot gives SFDR expressed in dBc and the right side gives HSL (Highest Spur Level excluding Fclock spur) expressed in dBm.





Données Freq_Out

NRZ mode is only relevant for Fout below 400 MHz.

The spikes in the SFDR are caused by normalization artefacts due to the Sinc(x) null.

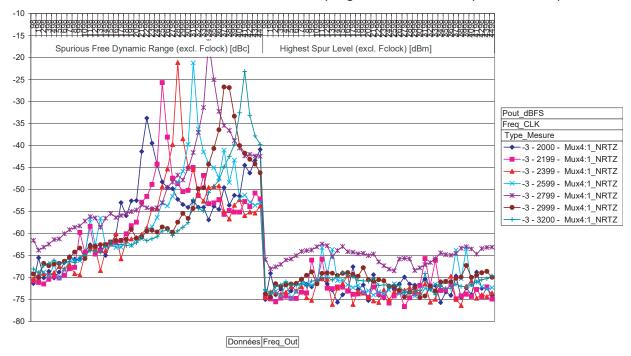
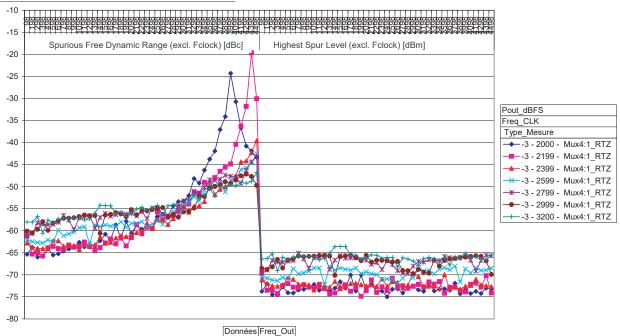


Figure 7-11. SFDR and HSL in NRTZ mode at -3 dBFS for Sampling Rate from 2000 MSps to 3200 MSps

NRTZ mode brings significant improvement regarding NRZ mode. This mode concentrates the benefits of both NRZ mode (high power available) and RTZ mode (extended available dynamic range). The spikes in the SFDR are caused by normalization artefacts due to the Sinc(x) null.

Figure 7-12. SFDR and HSL in RTZ Mode at –3 dBFS for Sampling Rate from 2000 MSps to 3200 MSps



RTZ mode allows for operation over the 3 first Nyquist zones.

In first and beginning of second Nyquist zone NRTZ mode is mode relevant. The spikes in the SFDR are caused by normalization artefacts due to the Sinc(x) null.

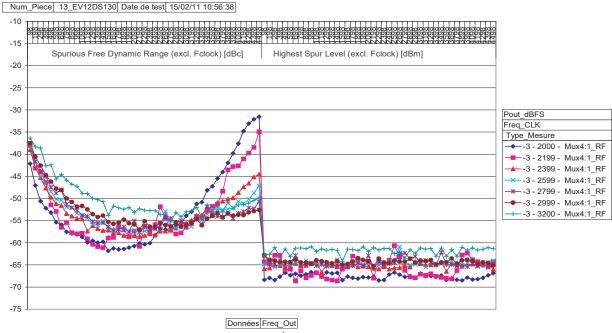
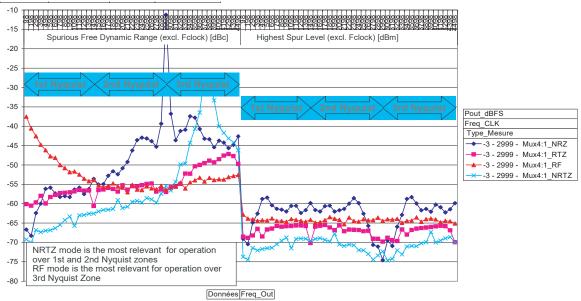


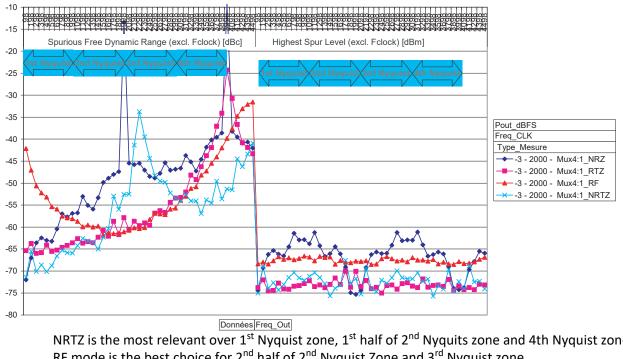
Figure 7-13. SFDR and HSL in RF Mode at -3 dBFS for Sampling Rate from 2000 MSps to 3200 MSps

RF mode allows for operation over 3rd Nyquist zones. Performances are not sensitive to output level. Performance roll off occurs beyond 3000 MSps.

Figure 7-14. Comparison of the 4 Output Modes at 2999 MSps and at –3 dBFS: SFDR and HSL



NRZ is interesting only at the very beginning of the first Nyquist zone. NRTZ is relevant over 1st 2nd and 4th Nyquist zones. RTZ is relevant over 2nd and 3rd Nyquist zones. RF mode displays a good behavior over 2nd and 3rd Nyquist Zones. The spikes in the SFDR are caused by normalization artefacts due to the Sinc(x) null

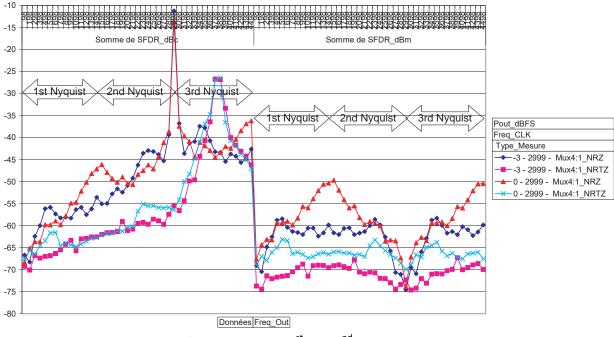




NRTZ is the most relevant over 1st Nyquist zone, 1st half of 2nd Nyquits zone and 4th Nyquist zone. RF mode is the best choice for 2nd half of 2nd Nyquist Zone and 3rd Nyquist zone. RTZ gives relevant performances over the three first Nyquist zones.

The spikes in the SFDR are caused by normalization artefacts due to the Sinc(x) null

Comparison of NRZ and NRTZ Modes at Full Scale and -3 dBFS at 2999 MSps: SFDR and HSL (Excluding Figure 7-16. Fclock)



NRTZ gives better performances over 1st and 2nd Nyquist zone, and is much less sensitive to output level.

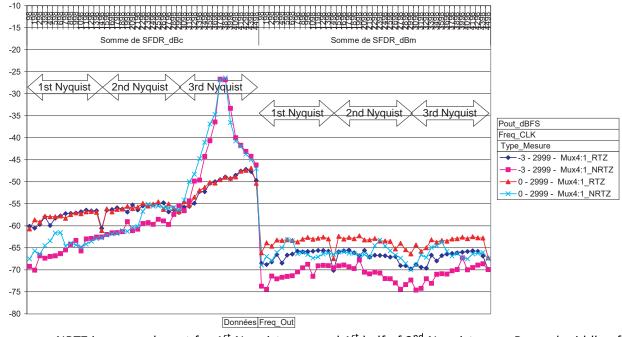
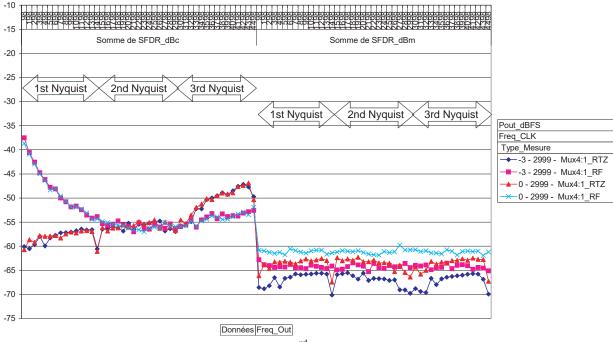
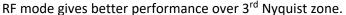


Figure 7-17. Comparison of NRTZ and RTZ Modes at Full Scale and –3 dBFS at 2999 MSps: SFDR and HSL

NRTZ is more relevant for 1st Nyquist zone and 1st half of 2nd Nyquist zone. Beyond middle of second Nyquist zone RTZ mode is more relevant.

Figure 7-18. Comparison of RTZ and RF Modes at Full Scale and –3 dBFS at 2999 MSps: SFDR and HSL





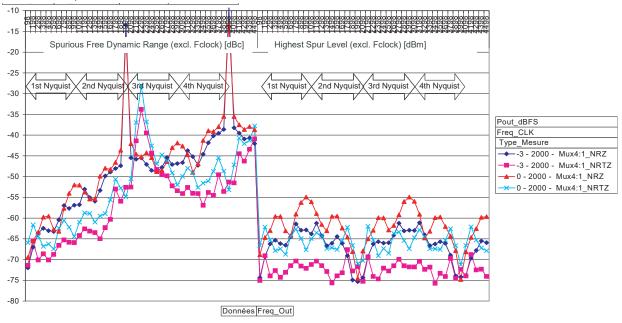
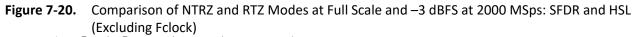
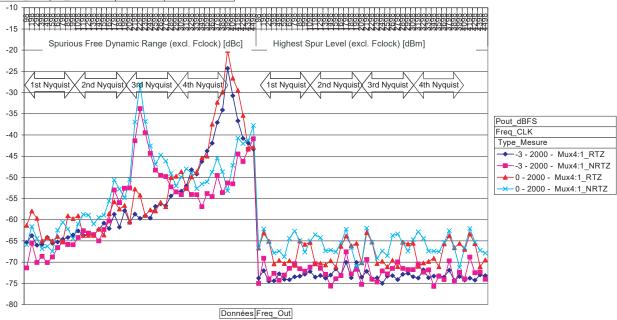


Figure 7-19. Comparison of NRZ and NRTZ Modes at Full Scale and –3 dBFS at 2000 MSps: SFDR and HSL (Excluding Fclock)

NRTZ linearity is slightly improved reducing the sampling rate to 2000 MSps, possibility of operation over the 4th Nyquist zone is demonstrated.



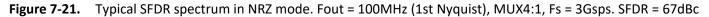


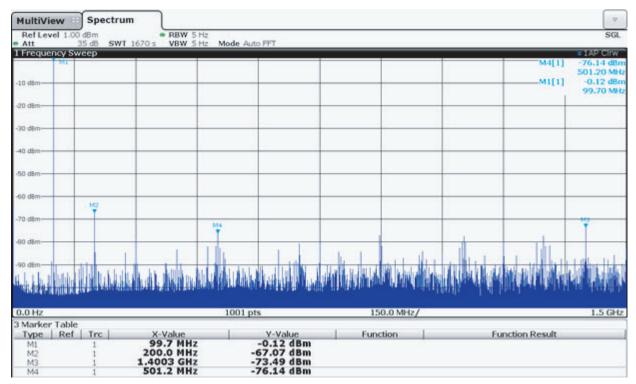
NRTZ mode is relevant in 1st, 2nd Nyquist zones and is still usable over 4th Nyquist zone with SFDR in excess of 50 dBc.

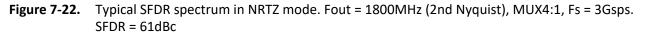
7.2.3 Single tone measurements: typical spectra at 3Gsps

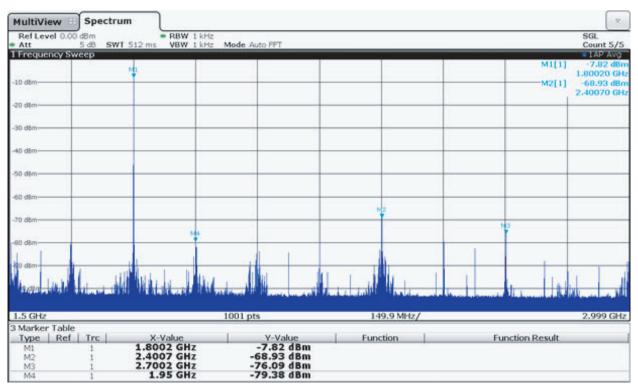
The following figures show typical SFDR spectra obtained for the four DAC modes on an EV12DS130A/B device.

Conditions: typical power supplies, ambient temperature, MUX4:1, Fs = 3 Gsps.









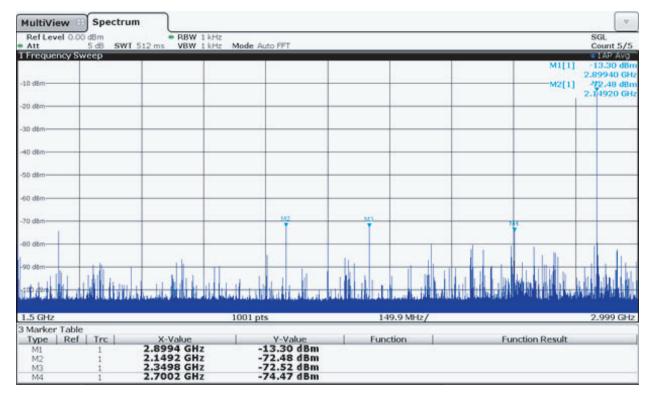
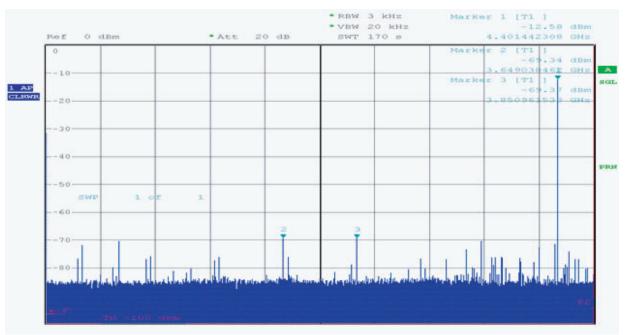


Figure 7-23. Typical SFDR spectrum in RTZ mode. Fout = 2900MHz (2nd Nyquist), MUX4:1, Fs = 3Gsps. SFDR = 59dBc.

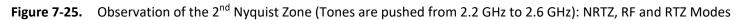
Figure 7-24. Typical SFDR spectrum in RF mode. Fout = 4400MHz (3rd Nyquist), MUX4:1, Fs = 3Gsps. SFDR = 56 dBc

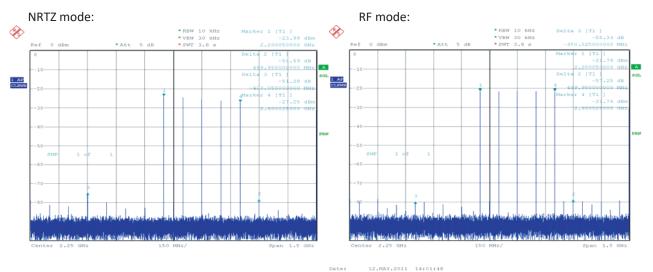


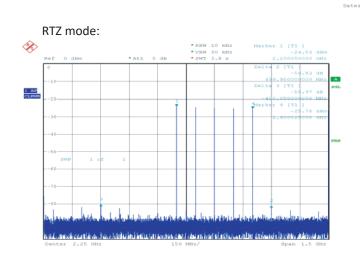
7.2.4 Multi Tone Measurements

A five tones pattern (400 MHz, 500 MHz, 600 MHz, 700 MHz and 800 MHz) is applied to the DAC operating at 3 Gsps and results are observed in the 2^{nd} , 3^{rd} , 4^{th} and 5^{th} Nyquist zones.

Results are given in the most relevant mode considering the Nyquist zone observed.







	Fout (MHz)	Pout (dBm)	SFDR (freq)	SFDR (dBc)
NRTZ	2200	-23,99	1800	-51,28
RTZ	2200	-24,53	1800	-55,97
RF	2200	-21,76	2700	-57,25

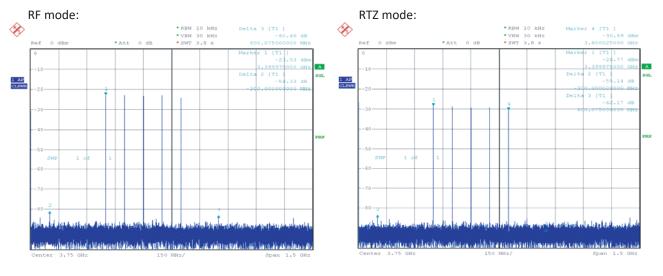
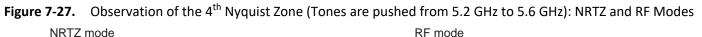
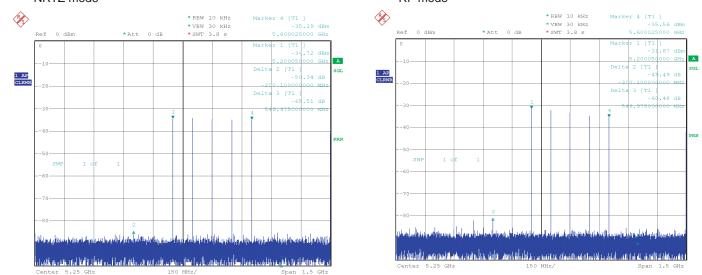


Figure 7-26. Observation of the 3rd Nyquist Zone (Tones are pushed from 3.4GHz to 3.8GHz): RF and RTZ Modes

	Fout (MHz)	Pout (dBm)	SFDR (freq)	SFDR (dBc)
NRTZ	3400	-39.43	4000	-44.48
RTZ	3400	-28.77	3100	-55.14
RF	3400	-23.03	3100	-58.33

NRTZ performances are degraded because of the sinc attenuation (first notch in the first half of the 3rd Nyquist zone).



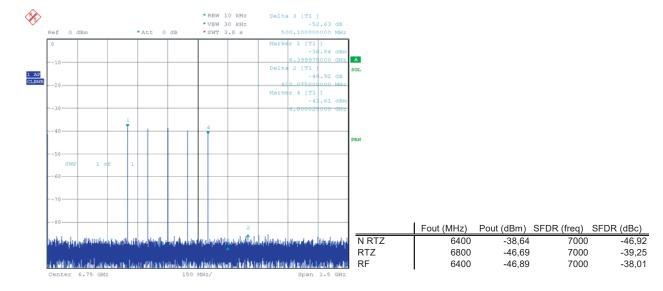


Fout (MHz)		Pout (dBm)	SFDR (freq)	SFDR (dBc)	
NRTZ	5200	-34.72	5000	-50.34	
RTZ	5200	-40.37	4700	-45	
RF	5200	-31.87	4700	-49.49	

RTZ mode is degraded because of the sinc attenuation (first notch at the end of the 4th Nyquist zone). RF mode offers significantly more power than RTZ mode, this is why we still have acceptable performances.

NRTZ operation is possible because the 4th Nyquist zone is fully included in the secondary spectral lobe.

Figure 7-28. Observation of the 5th Nyquist Zone (Tones are pushed from 6.4 GHz to 6.8 GHz): NRTZ Mode



NRTZ mode is still usable in the 5th Nyquist zone (SFDR in excess of 46 dB).

7.2.5 Direct Microwave Synthesis Capability Measurements: ACPR

Measurements given hereafter are performed on the DAC at 3 Gsps with a 10 MHz wide QPSK pattern centered on 800 MHz.

Results are observed in 2nd, 3rd, 4th and 5th Nyquist zones and are given only for the most relevant modes (that is RF and/or NRTZ modes).

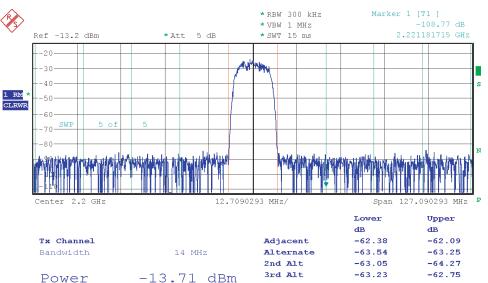


Figure 7-29. NRTZ Mode, 2nd Nyquist: Center Frequency is pushed to 3 GHz – 800 MHz = 2.2 GHz

ACPR is in excess of 62 dB. DMWS capability is proven for second Nyquist in NRTZ mode.

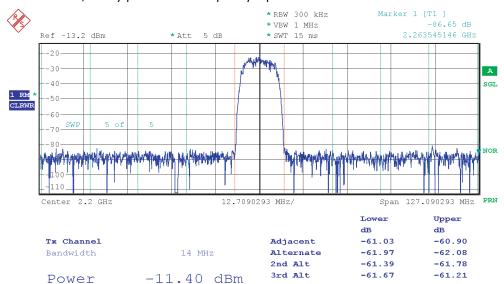


Figure 7-30. RF Mode, 2nd Nyquist: Center Frequency is pushed to 3 GHz – 800 MHz = 2.2 GHz

ACPR is in excess of 60 dB. DMWS capability is proven for the second Nyquist zone in RF mode with slightly reduced dynamic range regarding NRTZ mode but with increased output power.

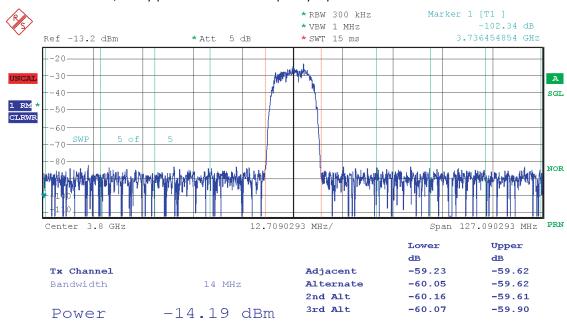


Figure 7-31. RF Mode, 3rd Nyquist Zone: Center Frequency is pushed to 3 GHz+ 800 MHz = 3.8 GHz

ACPR is in excess of 59 dB. DMWS capability is proven for the third Nyquist zone in RF mode.

Note: due to the notch of available Pout near the middle of the third Nyquist zone, the NRTZ mode is not relevant for DMWS in the third Nyquist zone.

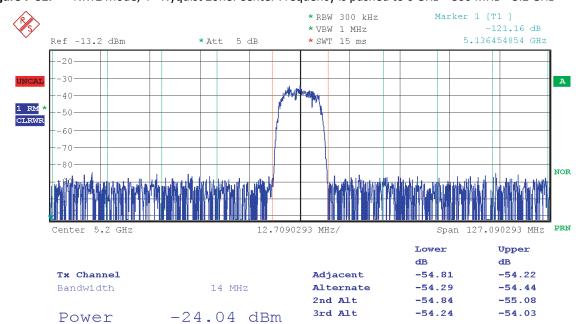


Figure 7-32. NRTZ Mode, 4th Nyquist Zone: Center Frequency is pushed to 6 GHz – 800 MHz = 5.2 GHz

ACPR is in excess of 54 dB. DMWS capability is proven for the fourth Nyquist zone in NRTZ mode.

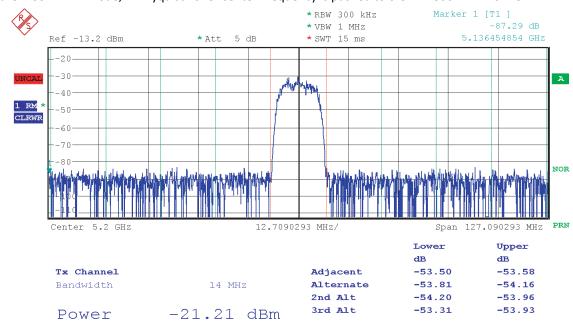


Figure 7-33. RF Mode, 4th Nyquist Zone: Center Frequency is pushed to 6 GHz – 800 MHz = 5.2 GHz

ACPR is in excess of 53 dB. DMWS capability is proven for the fourth Nyquist zone in RF mode.

Note due to a notch of available Pout near the end of the 4th Nyquist zone in RF output mode, for DMWS beyond middle of 4th Nyquist zone it is recommended to use the NRTZ output mode instead of the RF output mode.

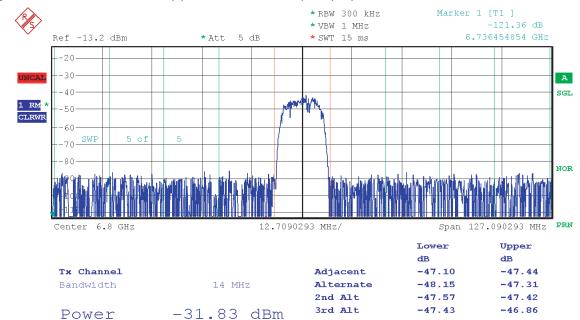


Figure 7-34. NRTZ Mode, 5th Nyquist Zone: Center Frequency is pushed to 6 GHz + 800 MHz = 6.8 GHz

ACPR is still in excess of 47 dB. DMWS capability if proven for the fifth Nyquist zone in NRTZ mode with reduced available dynamic range.

7.2.6 DOCSIS v3.0 Capability Measurements

Measurements hereafter have been carried out on a soldered device EV12DS130A/B, in NRTZ mode at 3 GSps.

Note: Results illustrated hereafter (spectrum and zoom on notch) come from measurement on a EV12DS130A/B device (CI-CGA255 package). Measurements have been carried out using the ACP treatment of the spectrum analyzer Rhode & Schwarz FSU8, in RMS detection mode.

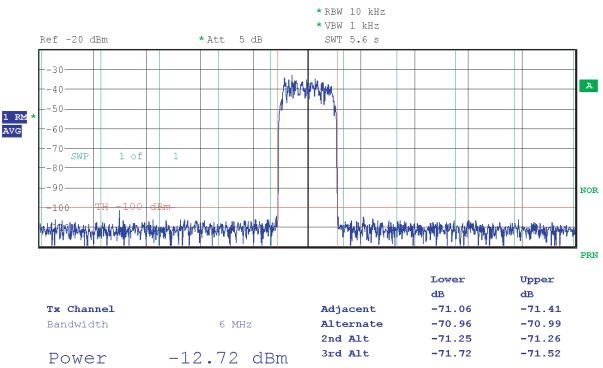


Figure 7-35. ACPR 1 Channel Centered on 300 MHz, Output Mode NRTZ

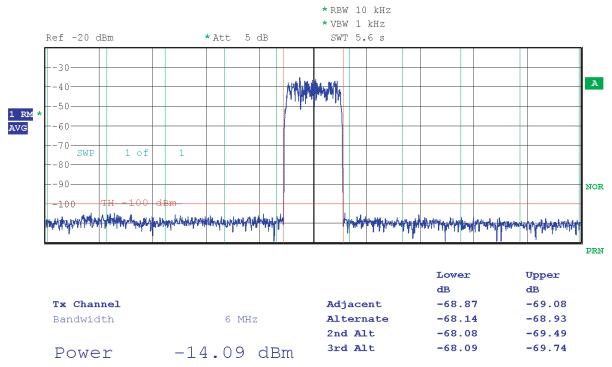
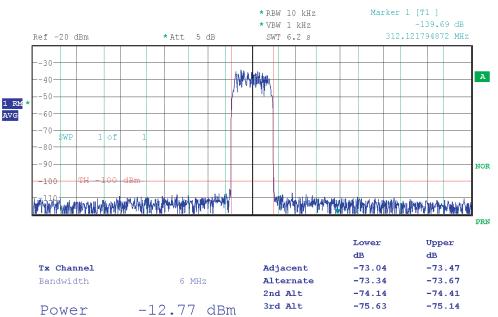


Figure 7-36. ACPR 1 Channel Centered on 900 MHz, Output Mode NRTZ





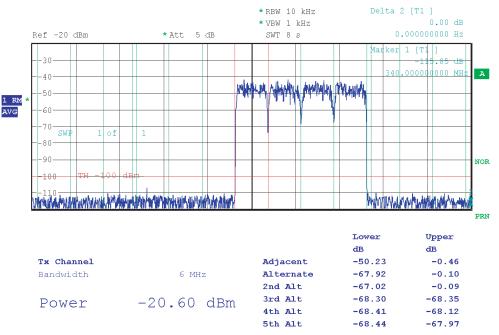
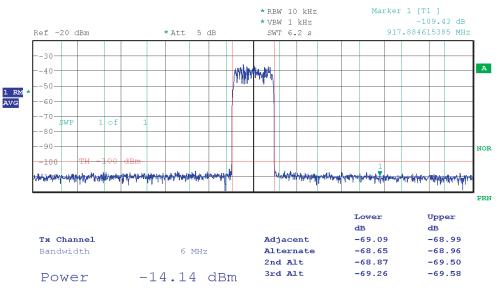


Figure 7-38. ACPR 4 Channels Centered on 300 MHz, Output Mode NRTZ





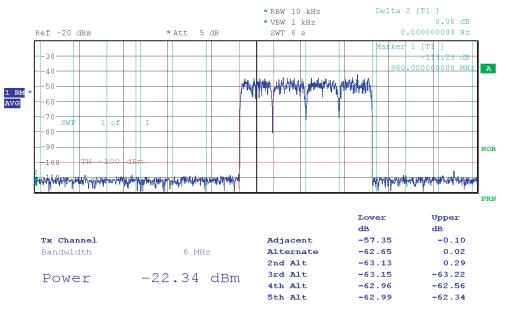


Figure 7-40. ACPR 4 Channels Centered on 900 MHz, Output Mode NRTZ

7.2.7 NPR Performance

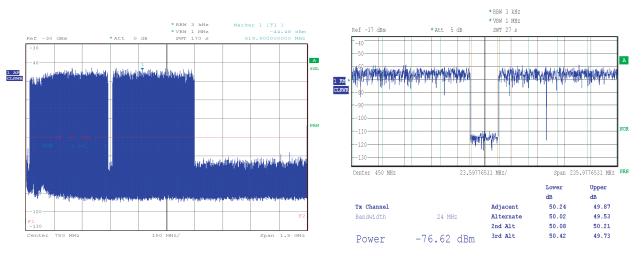
NPR measurements have been carried out at optimum loading factor (LF) for a 12 bit DAC, that is – 14 dBFS, with the DAC operating at 3 Gsps.

SNR can be computed from SNR measurement with the formula: $SNR_{fdB1} = NPR_{fdB1} + ILF_{fdB1}I - 3$.

ENOB can be computed with the formula: ENOB = $(SNR_{[dB]} - 1.76) / 6.02$.

Note: Results illustrated hereafter (spectrum and zoom on notch) come from measurement on a EV12DS130A/B device (CI-CGA255 package). Measurements have been carried out using the ACP treatment of the spectrum analyzer Rhode & Schwarz FSU8, in RMS detection mode.

Figure 7-41. NPR in First Nyquist Zone, 20 MHz to 900 MHz Noise Pattern with a 25 MHz Notch Centered on 450 MHz, NRZ mode



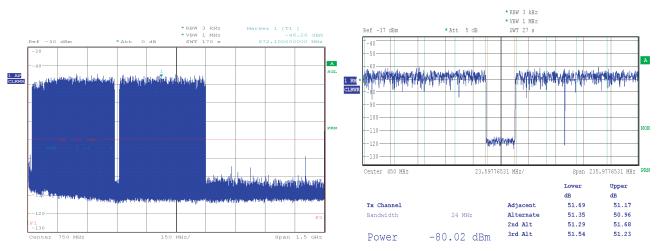
Measured average NPR: 50.02 dB, therefore SNR = 61.02 dB and ENOB = 9.84 bit

Effects at low frequency are due to balun and pattern.

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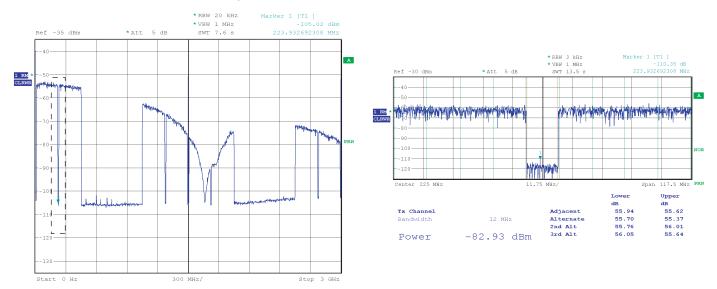
58

Figure 7-42. NPR in First Nyquist Zone, 20 MHz to 900 MHz Noise Pattern with a 25 MHz Notch Centered on 450 MHz, NRTZ Mode



Measured average NPR: 51.36 dB, therefore SNR = 62.36 dB and ENOB = 10.07 bit. Effects at low frequency are due to balun and pattern.

Figure 7-43. NPR in First Nyquist Zone, 10 MHz to 450 MHz Noise Pattern with a 12.5 MHz Notch centered on 225 MHz, NRTZ Mode at Fs = 1.5 Gsps



Measured average NPR: 55.7 dB, therefore SNR = 66.7 dB and ENOB = 10.8 bit. Effects at low frequency are due to balun and pattern.

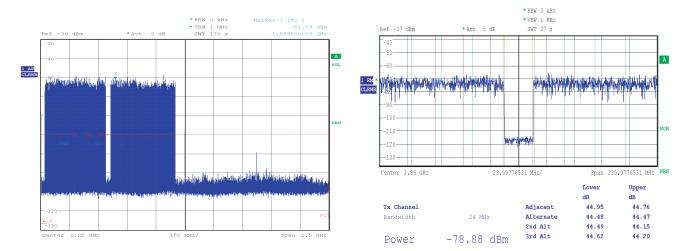
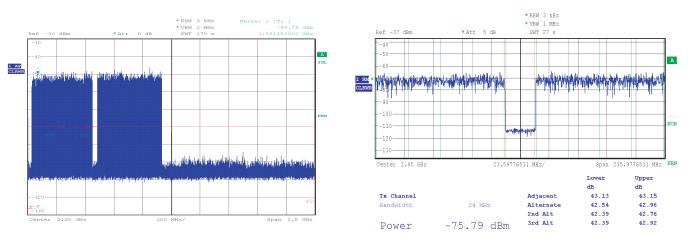


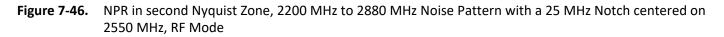
Figure 7-44. NPR in second Nyquist Zone, 1520 MHz to 2200 MHz Noise Pattern with a 25 MHz Notch centered on 1850 MHz, RTZ mode

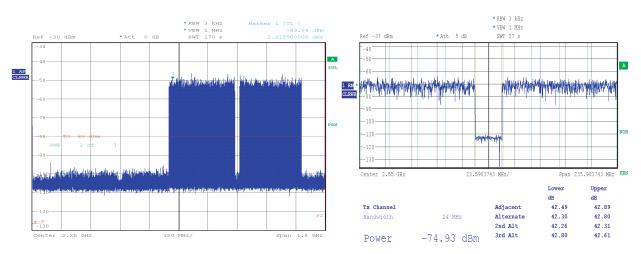
Measured average NPR: 44.6 dB, therefore SNR = 55.6 dB and ENOB = 8.94 bit

Figure 7-45. NPR in second Nyquist Zone, 1520 MHz to 2200 MHz noise pattern with a 25 MHz notch centered on 1850 MHz, RF Mode

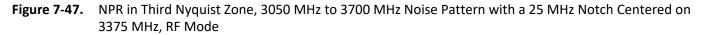


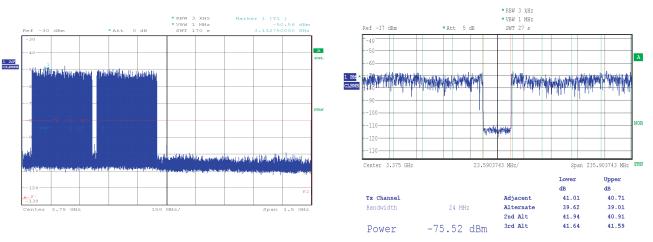
Measured average NPR: 42.78 dB, therefore SNR = 53.78 dB and ENOB = 8.64 bit





Measured average NPR: 42.56 dB, therefore SNR = 53.56 dB and ENOB = 8.6 bit.





Measured average NPR: 40.08 dB, therefore SNR = 51.08 dB and ENOB = 8.19 bit

The following figures reflect the stability of NPR in first Nyquist in NRTZ mode (and therefore SNR and ENOB) versus temperature.

Measurements have been carried out at nominal power supply on an EV12DS130A/B, at 3 Gsps, with the FSU8 spectrum analyzer in RMS detection mode.

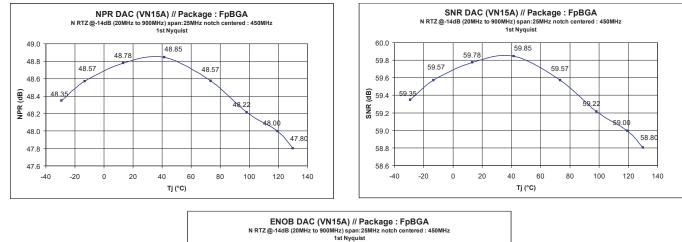
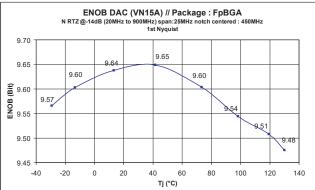
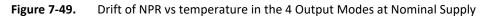


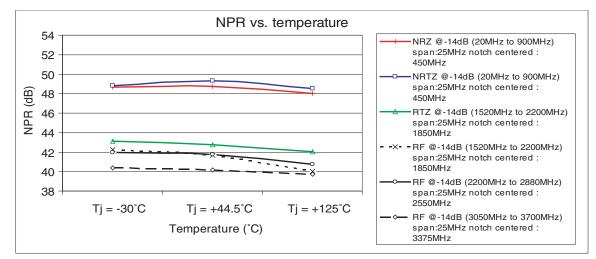
Figure 7-48. Drift of NPR and Associated SNR and ENOB in First Nyquist in NRTZ Mode from Tj = -30°C to Tj = 125°C



Optimum is at Tj = 40°C, degradation over temp is within 1 dB (or 0.15 effective bit).

Measurements hereafter have been carried out on an EV12AS130AGS device at 3 Gsps, with the FSU8 spectrum analyzer in RMS detection mode.





Conclusion: performances are stable in the four output modes against temperature.

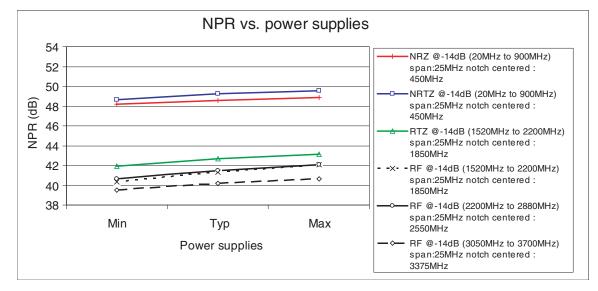


Figure 7-50. NPR vs Power Supply Level in the 4 Output Modes at Room Temperature

Conditions: Typical, excepted: power supplies

Min: V_{CCA} : 4.75V // V_{CCA3} = V_{CCD} = 3.15V

Typ: V_{CCA} : 5.0V // $V_{CCA3} = V_{CCD} = 3.3V$

Max: V_{CCA} : 5.25V // V_{CCA3} = V_{CCD} = 3.45V.

Conclusion: performances are fairly stable against power supply.

Note: NPR performance at lower clock frequencies is affected by power up sequence. See application note 1087 for further details.

7.2.8 Spectrum over 4 Nyquist Zones in the Four Output Modes

Observation of a 1GHz broadband pattern with a 25 MHz notch centered on 500 MHz spectrum over 4 Nyquist zones at 3 Gsps (that is from DC to 6 GHz), measurements performed on an EV12DS130A/B device (CI-CGA 255 package, with an overall 6 GHz bandwidth limitation).

By periodisation of a sampled system each tone F_i of the pattern in the 1st Nyquist zone is duplicated as follows:

- 2nd Nyquist Zone: tone at Fclock F_i
- 3rd Nyquist Zone: tone at Fclock + F_i
- 4th Nyquist Zone: tone at 2*Fclock F_i

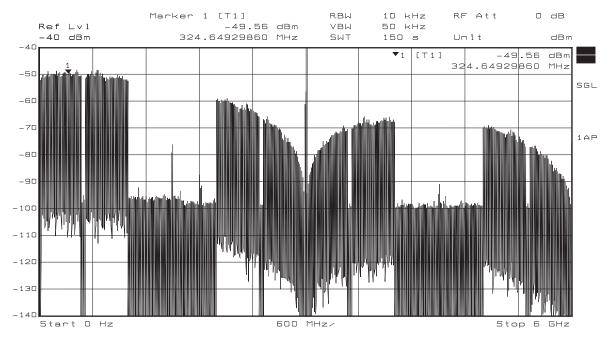
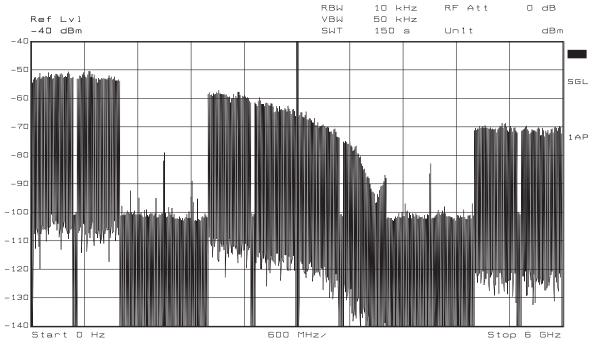


Figure 7-51. Spectrum over 4 Nyquist Zones at 3 Gsps in NRZ Output Mode

First Zero of the sinc() function is at Fclock.





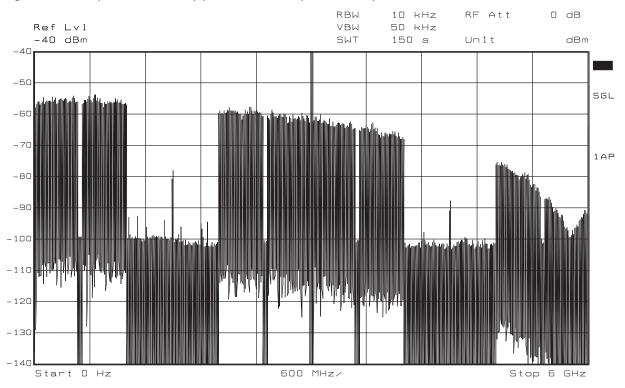


Figure 7-53. Spectrum over 4 Nyquist Zones at 3 Gsps in RTZ Output Mode

First Zero of the sinc() function is slightly before 2*Fclock which indicates that the duty cycle of RTZ function is a little bit more than 50%, this is due to the balun which introduced some phase error beyond the 180 degrees between CLK and CLKN thus creating a duty cycle on the clock actually seen by the DAC.

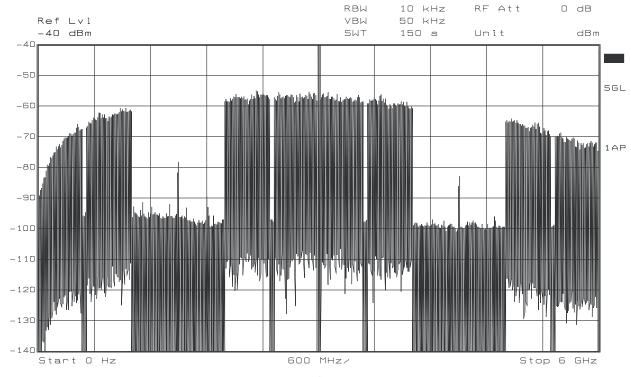


Figure 7-54. Spectrum over 4 Nyquist Zones at 3 Gsps in RF Output Mode

Measurements are showing a pretty good fit with theory, see Section 5.3 on page 17.

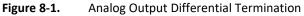
8. APPLICATION INFORMATION

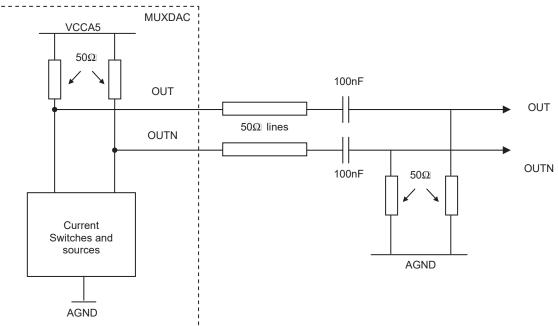
For further details, please refer to application note 1087.

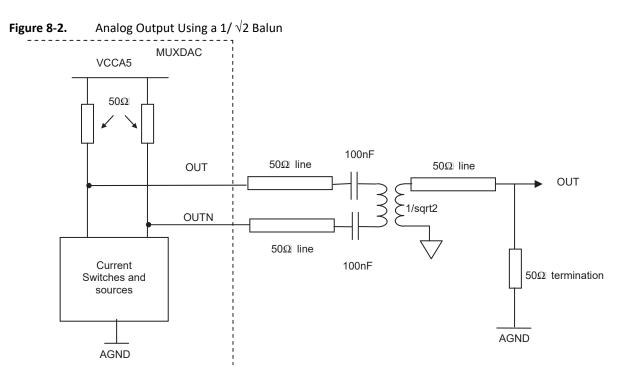
8.1 Analog Output (OUT/OUTN)

The analog output should be used in differential way as described in the figures below.

If the application requires a single-ended analog output, then a balun is necessary to generate a singleended signal from the differential output of the DAC.







Note: The AC coupling capacitors should be chosen as broadband capacitors with a value depending on the application.

8.2 Clock Input (CLK/CLKN)

The DAC input clock (sampling clock) should be entered in differential mode as described in Figure 5-9.

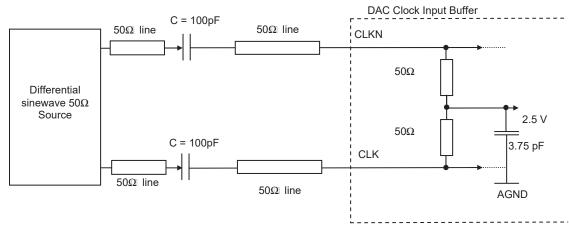
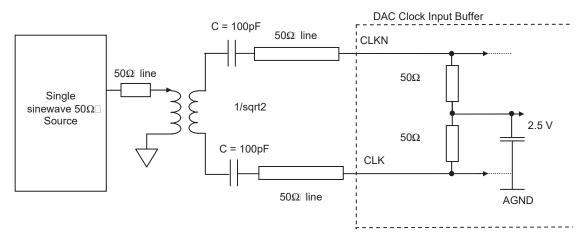


Figure 8-3. Clock Input Differential Termination

Note: The buffer is internally pre-polarized to 2.5V (buffer between V_{CC5} and AGND).

Figure 8-4. Clock Input Differential with Balun

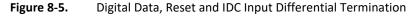


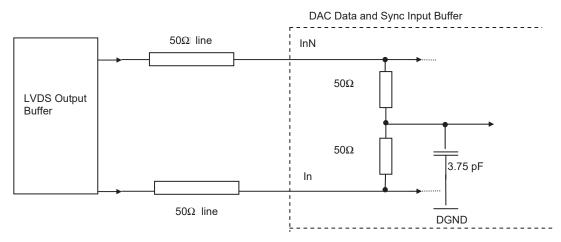
Note: The AC coupling capacitors should be chosen as broadband capacitors with a value depending on the application.

8.3 Digital Data, SYNC and IDC Inputs

LVDS buffers are used for the digital input data, the reset signal (active high) and IDC signal.

They are all internally terminated by $2 \times 50\Omega$ to ground via a 3.75 pF capacitor.





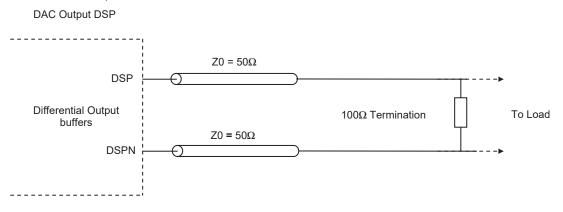
- Notes: 1. In the case when only two ports are used (2:1 MUX ratio), then the unused data should be left open (no connect).
 - 2. Data and IDC signals should be routed on board with the same layout rules and the same length than the data.
 - 3. In case SYNC is not used, it is necessary to bias the SYNC to 1.1V and SYNCN to 1.4V on EV12DS130A.

8.4 DSP Clock

The DSP, DSPN output clock signals are LVDS compatible.

They have to be terminated via a differential 100Ω termination as described in Figure 5-11.

Figure 8-6. DSP Output Differential Termination



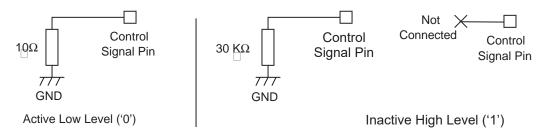
8.5 Control Signal Settings

The MUX, MODE, PSS and OCDS control signals use the same static input buffer.

Logic "1" = 200 K Ω to Ground, or tied to V $_{\text{CCD}}$ = 3.3V or left open

Logic "0" = 10Ω to Ground or Grounded

Figure 8-7. Control Signal Settings



The control signal can be driven by FPGA.





Logic "1" > V_{IH} or V_{CCD} = 3.3V Logic "0" < V_{IL} or 0V

8.6 HTVF and STVF Control Signal

The HTVF and STVF control signals is a 3.3V CMOS output buffer.

These signals could be acquired by FPGA.



FPGA HTVF STVF Control Signal

In order to modify the V_{OL}/V_{OH} value, pull up and pull down resistances could be used, or a potential divider.

8.7 GA Function Signal

This function allows adjustment of the internal gain of the DAC.

The gain of the DAC can be tuned with applied analog voltage from 0 to V_{CCA3}

This analog input signal could be generated by a DAC controlled by FPGA or microcontroller.

Figure 8-10. Control Signal Settings with GA



8.8 Power Supplies Decoupling and Bypassing

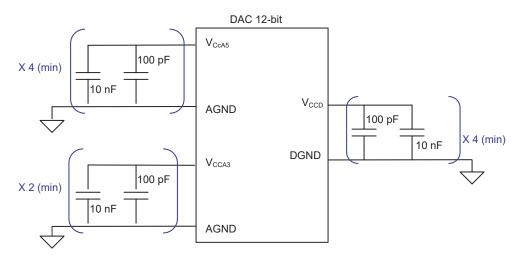
The DAC requires 3 distinct power supplies:

 $V_{CCA5} = 5.0V$ (for the analog core) $V_{CCA3} = 3.3V$ (for the analog part) $V_{CCD} = 3.3V$ (for the digital part)

It is recommended to decouple all power supplies to ground as close as possible to the device balls with 100 pF in parallel to 10nF capacitors. The minimum number of decoupling pairs of capacitors can be calculated as the minimum number of groups of neighboring pins.

4 pairs of 100pF in parallel to 10 nF capacitors are required for the decoupling of V_{CCA5} . 4 pairs for the V_{CCA3} is the minimum required and finally, 10 pairs are necessary for V_{CCD} .

Figure 8-11. Power Supplies Decoupling Scheme



Each power supply has to be bypassed as close as possible to its source or access by 100 nF in parallel to 22 μ F capacitors (value depending of DC/DC regulators).

Analog and digital ground plane should be merged.

8.9 Power Up Sequencing

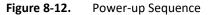
For EV12DS130B there is no forbidden power-up sequence, nor power supplies dependency requirement.

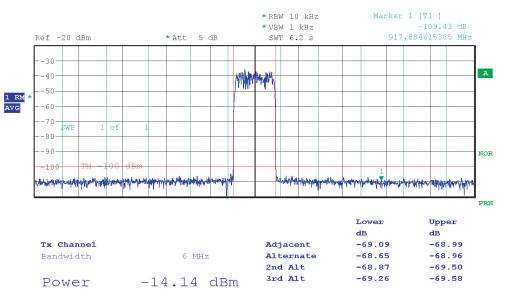
For EV12DS130A the following instructions must be implemented:

Power-up sequence:

It is necessary to raise V_{CCA5} power supply within the range 5.20V up to a recommended maximum of 5.60V during at least 1ms at power up. Then the supply voltage has to settle within 500 ms to a steady nominal supply voltage within a range of 4.75V up to 5.25V.

A power-up sequence on V_{CCA5} that does not comply with the above recommendation will not compromise the functional operation of the device. Only the noise floor will be affected.





The rise time for any of the power supplies (V_{CCA5} , V_{CCA3} and V_{CCD}) shall be \leq 10 ms.

At power-up a SYNC pulse is internally and automatically generated when the following sequence is satisfied: V_{CCD} , V_{CCA3} and V_{CCA5} . To cancel the SYNC pulse at power-up, it is necessary to apply the sequence: V_{CCA5} , V_{CCA3} , V_{CCD} . (It is mandatory that V_{CCD} is the last supply to rise and always remains behind V_{CCA5} and V_{CCA3}). Any other sequence may not have a deterministic SYNC behaviour. See erratasheet (ref 1125) for specific condition of use relative to the SYNC operation.

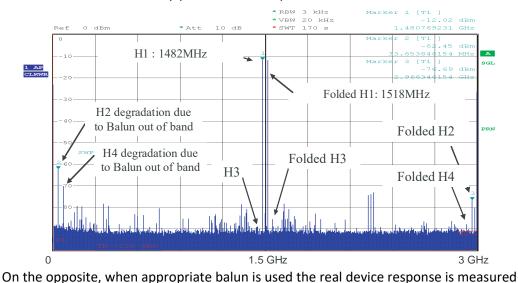
Relationship between power supplies:

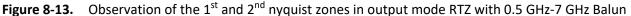
Within the applicable power supplies range, the following relationship shall always be satisfied $V_{CCA3} \ge V_{CCD}$, taking into account AGND and DGND planes are merged and power supplies accuracy.

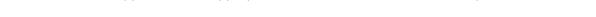
8.10 Balun Influence

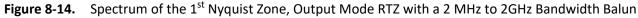
It is important to know that balun characteristic may influence significantly DAC output spectral response. Especially harmonic distortion can dramatically be degraded when part of the band of interest lies out of the specified domain of the balun.

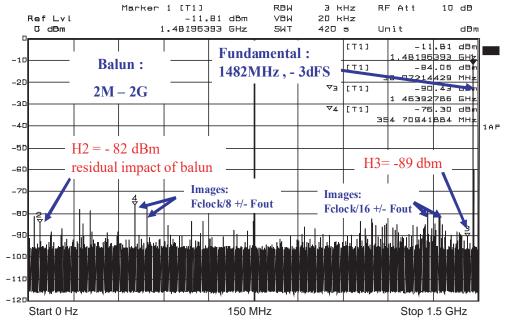
As depicted in the following figure an inappropriate balun choice can result in a strong increase in harmonic peaks amplitude, thus degrading performances. The balun used in this measurement covers only the 500MHz to 7GHz band so that the DC to 500MHz region of the first nyquist zone is distorted.







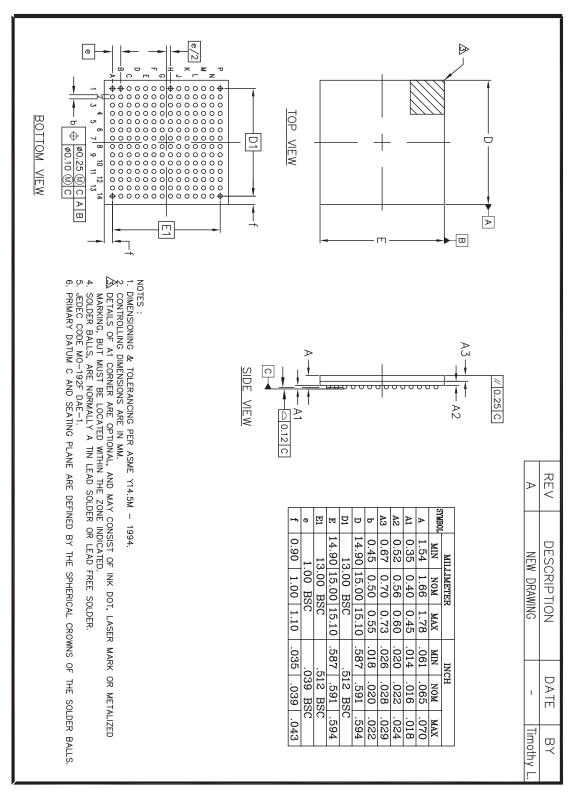




As a consequence, one must be aware that optimum performances can only be reached when using a balun optimal for the band of interest of the application. We specifically recommend selecting a balun which frequency domain covers the whole band of interest (for instance one whole Nyquist zone).

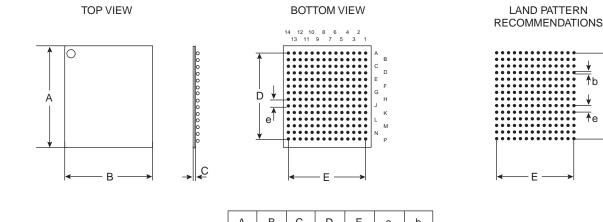
9. PACKAGE INFORMATION

9.1 fpBGA 196 Outline



9.2 Land Pattern Recommendation

Figure 9-1. Land Pattern Recommendation



А	В	С	D	Е	е	b
15.00	15.00	1.21	13.00	13.00	1.00	0.45

10. THERMAL CHARACTERISTICS FPBGA196

10.1 **Thermal Resistance**

Assumptions:

Still air Pure conduction No radiation

Heating zone = 5% of die surface

Rth Junction – bottom of Balls = 13.3°C/W Rth Junction – board (JEDEC JESD-51-8) = 17.8°C/W Rth Junction – top of case = $14.5^{\circ}C/W$

Assumptions:

Heating zone = 5% of die surface Still air, JEDEC condition Rth Junction – ambient (JEDEC) = 32°C/W

11. DIFFERENCES BETWEEN EV12DS130A AND EV12DS130B

EV12DS130A and EV12DS130B exhibit the same dynamic performances.

EV12DS130B requires no specific dependency between power supplies nor power up sequences while the EV12DS130A does require specific power up sequences as described in Section 8.9 on page 72.

Maximum supported sampling frequency with DSP clock feature for EV12DS130B is 2.1GHz due to internal jitter. It is however possible to benefit from the EV12DS130B DAC performances up to 3GHz if specific system architecture is implemented. Please refer to application AN1141 for further information.

An Important Notice at the end of this datasheet addresses availability, warranty, changes, use in critical applications, intellectual property matters and other important disclaimers

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Ťe

D

No SYNC timing constraints (other than T1 T2) are required on EV12DS130B.

As a summary

When using EV12DS130A, please ensure your system fulfills those specific recommendations

- Power Up Sequence (See Section 8.9 on page 72)
- Power supplies dependency (see Section 8.9 on page 72)
- SYNC pin have to be driven in any case
- Please refer to errata sheet 1125

When using EV12DS130B, please ensure your system fulfills those specific recommendations

• In case sampling frequency is above 2.1 Gsps, please read the AN1141 "Using EV1xDS130B at sampling rate higher than 2.1GSps"

Please refer to application note AN1140 "Replacing EV1xDS130A with EV1xDS130B" for further details

12. ORDERING INFORMATION

Please refer to datasheet details and application notes before ordering.

Part Number	Package	Lead Finish	Temperature Range	Screening Level	Comments
			EV12DS130A		
EVX12DS130AZPY	fpBGA196 RoHS	SAC 305	Ambient	Prototype	
EV12DS130ACZPY	fpBGA196 RoHS	SAC 305	0°C < Tc, Tj < 90°C	Commercial « C » Grade	
EV12DS130AVZPY	fpBGA196 RoHS	SAC 305	–40°C < Tc, Tj < 110°C	Industrial « V » Grade	
EV12DS130AZPY-EB	fpBGA196 RoHS	NA	Ambient	Prototype	Evaluation board
EVX12DS130AZP	fpBGA196	SnPb 63/37	Ambient	Prototype	Contact sales for availability
EV12DS130AVZP	fpBGA196	SnPb 63/37	–40°C < Tc, Tj < 110°C	Industrial « V » Grade	Contact sales for availability
			EV12DS130B		
EVX12DS130BZPY	fpBGA196 RoHS	SAC 305	Ambient	Prototype	
EV12DS130BCZPY	fpBGA196 RoHS	SAC 305	0°C < Tc, Tj < 90°C	Commercial « C » Grade	
EV12DS130BVZPY	fpBGA196 RoHS	SAC 305	−40°C < Tc, Tj < 110°C	Industrial « V » Grade	
EV12DS130BZPY-EB	fpBGA196 RoHS	NA	Ambient	Prototype	Evaluation board
EV12DS130BVZP	fpBGA196	SnPb 63/37	–40°C < Tc, Tj < 110°C	Industrial « V » Grade	Contact sales for availability

Table 12-1.Ordering Information

13. REVISION HISTORY

This table provides revision history for this document.

Table 13-1.Revision History

Rev. No	Date	Substantive Change(s)
DS 60S 223692(K)	September 2023	Table 3-8 on page 11Change T1 typical value to 350psChange T2 typical value to 330psModify note 5 to: "The SYNC signal is captured on the falling edge of the master clock and is activehigh. Refer to Figure 3-3 on page 13.Replace Figure 3-3. SYNC Timing Diagram
1077J	August 2016	Section 9.1 "fpBGA 196 Outline" on page 75: Package drawing update Typo correction
10771	April 2016	Table 6-1 on page 29: Ports A, B, C and D description update
1077H	December 2014	Table 6-1 on page 28: V _{CCD} pin F10 added Section 5.5 on page 23: OCDS [10] not allowed
1077G	November 2014	Figure 1-1 on page 2: Typo error
1077F	October 2014	Introduction and description of EV12DS130B New Section 11. "Differences between EV12DS130A and EV12DS130B" on page 76 Table 3-9, "Coding Table (Theorical values)," on page 13: typo error on lines (RTZ) and (NRTZ) Section 5.1 "DSP Output Clock" on page 16 updated Section 5.3 "MODE Function" on page 17: equations updated Section 5.4 "PSS (Phase Shift Select Function)" on page 21 updated Section 5.8 "Synchronization functions for multi-DAC operation" on page 26 updated Figure 7-5 on page 38 updated Figure 7-13 on page 42 updated New Section 7.2.3 "Single tone measurements: typical spectra at 3Gsps" on page 46 New Section 8.10 "Balun Influence" on page 73 Table 12-1, "Ordering Information," on page 77 added column Lead Finish and added part number EV12DS130AVZP and all EV12DS130B part numbers
1077E	December 2013	Table 3-3, "Electrical Characteristics," on page 5: typo error on note 7: $V_{CCA3} \ge V_{CCD}$
1077D	December 2013	Table 3-2, "Recommended Conditions of Use," on page 4: typo error on note 2: $V_{CCA3} \ge V_{CCD}$
1077C	November 2013	Typo errors corrections OCDS restrictions to OCDS1 & 2 HTVF STVF flag application clarifications Power sequencing modification, relative to SYNC operation
1077В	July 2012	Typo errors corrections Absolute max rating clarifications Addition of pin equivalent schematic description Power up sequencing recommendation
1077A	February 2012	Initial revision

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IMPORTANT NOTICE

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